



ADS 2008  
January 2008  
Advanced Design System Quick Start

# Advanced Design System 2008

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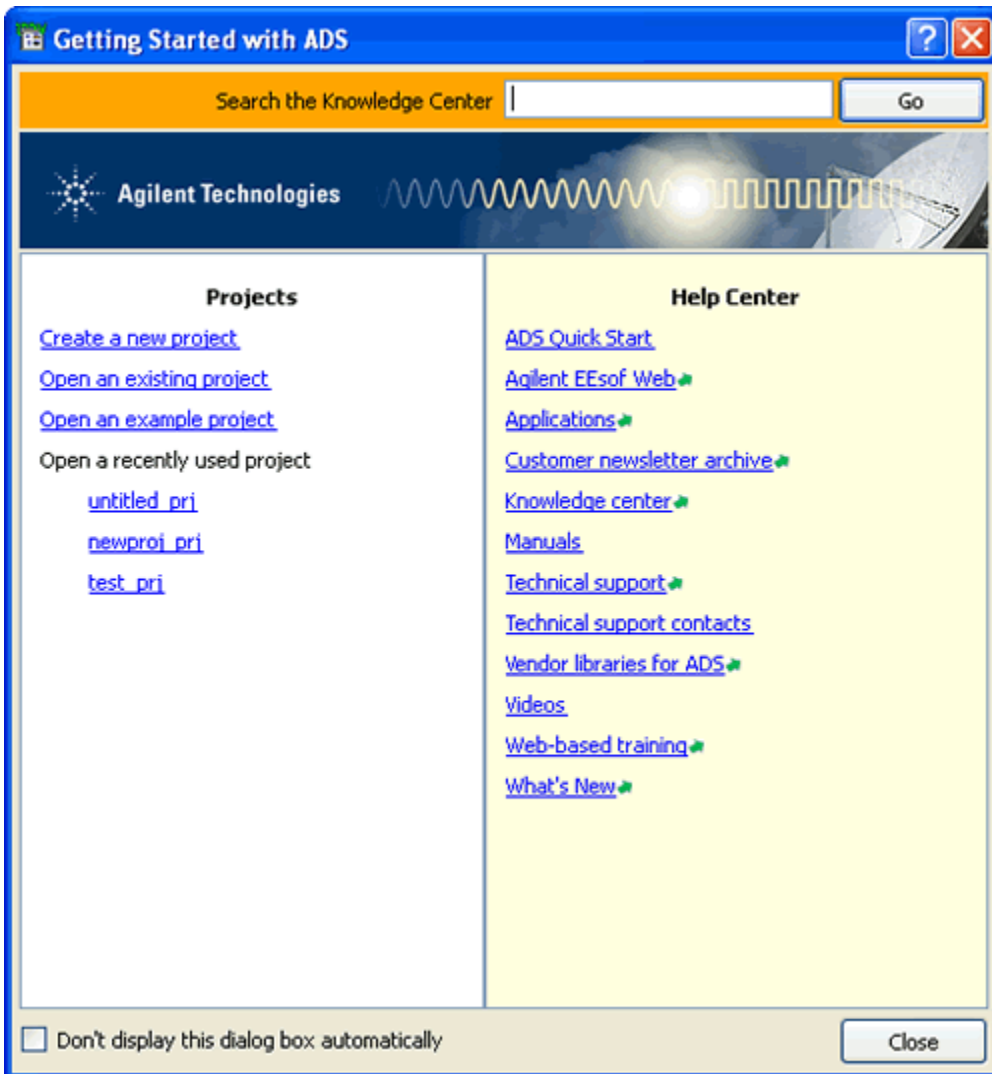
## Using Projects

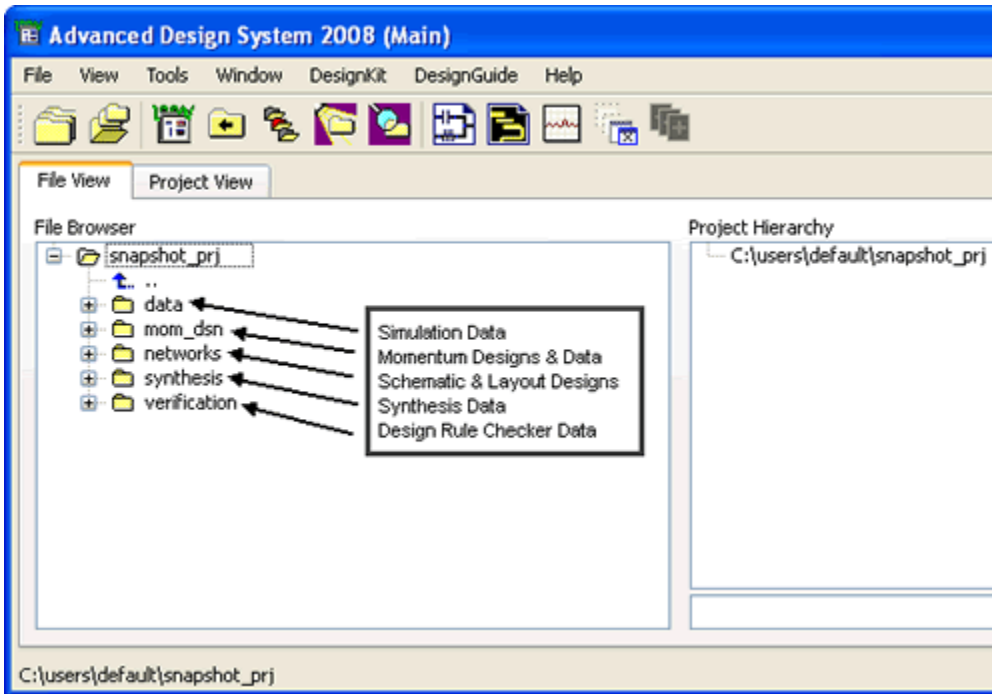
Advanced Design System uses projects to organize and store the data generated when you create, simulate, and analyze designs to accomplish your design goals.

## Advanced Design System 2008

A project includes circuit, layout, simulation, analysis, and output information on the designs that you create, along with any links you add to other designs and projects.

Use the Main window or the Getting Started with ADS dialog, to create and open projects. Both windows are displayed when you launch Advanced Design System.



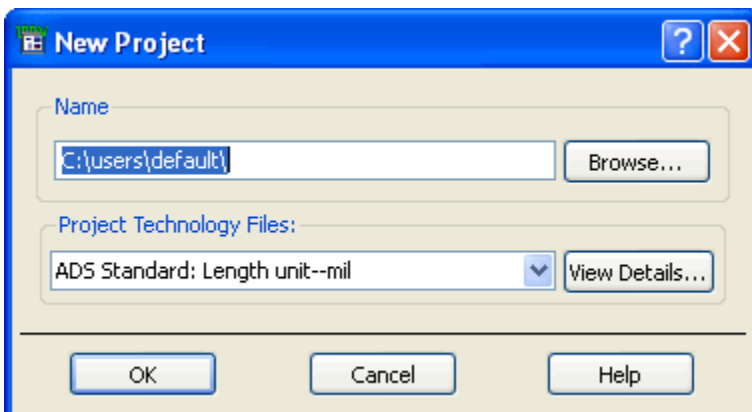


## Creating Projects

Use the Main window to create a project that you can then use to organize your designs. A project includes circuit, layout, simulation, analysis, and output information on the designs that you create, along with any links you add to other designs and projects.

To create a project...

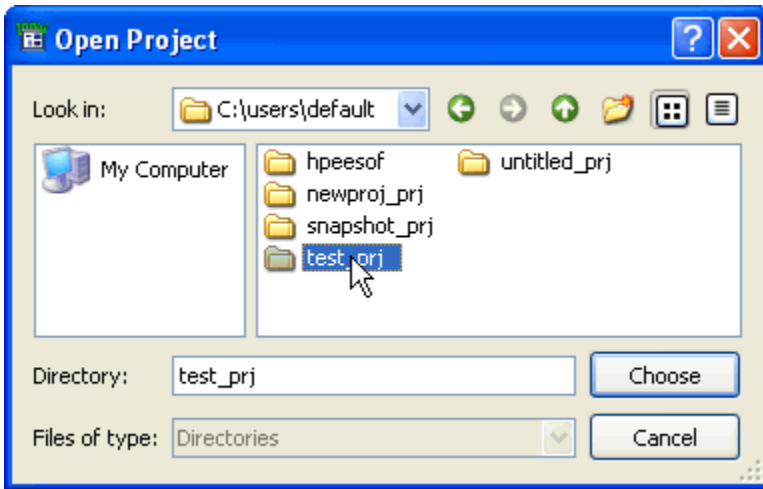
1. Choose File > New Project
2. Enter Project Name & Location



## Opening Projects

Only one project can be open at a time. When you begin to open a project, you are prompted to save any changes you have made in the currently open project before it is closed automatically.

To open a project choose File > Open Project and use the dialog box to locate and open the project.



## Sharing Projects

Use the Main Window to reuse and share projects without having to manually include all the individual parts that make up a project.

## Including Projects

Add links to another project to create a hierarchical project. Hierarchical projects offer several benefits:

- Referencing designs from other projects
- Maintaining a single source of designs
- Reducing disk space required by sharing designs

To include projects choose File > Include/Remove Projects and use the dialog box to locate and link to the project.

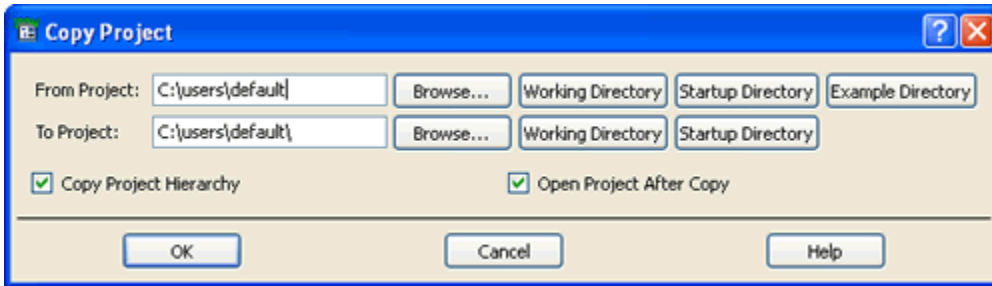
## Copying Projects

## Advanced Design System 2008

Create a copy to replicate a project. Copying a project directory and its contents to a new project directory allows you to save time and effort by using an existing project as a template.

**i** Note Copying projects should only be done through the program, as described here. Copying projects outside the program may result in invalid projects.

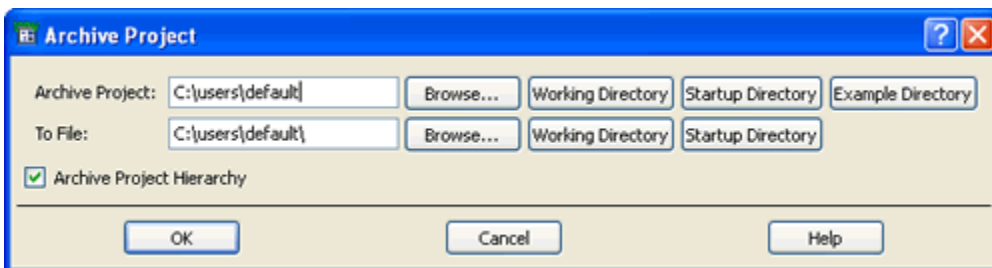
To copy projects choose File > Copy Project and use the dialog box to locate and copy the desired project.



### Archiving Projects

Archive/Unarchive projects to transfer a compact project archive. Creating a single file for a project simplifies transferring projects to another file system or to another location on the same file system.

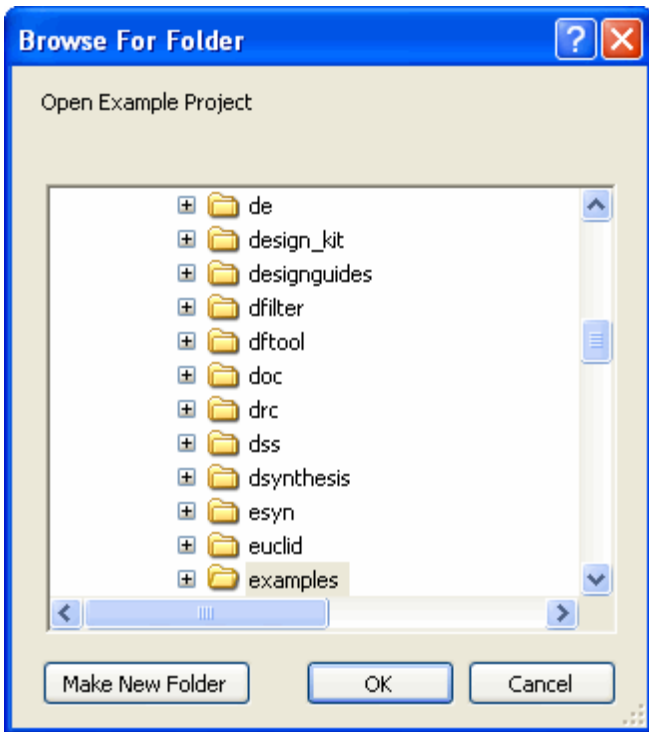
To archive projects choose File > Archive Project and use the dialog box to locate and archive the project.



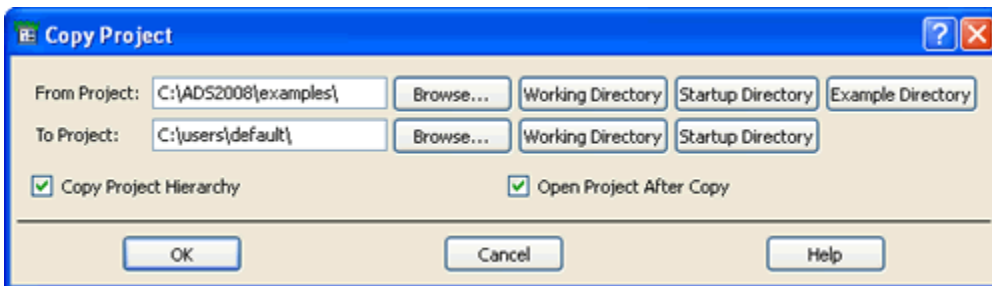
### Using Example Projects

Advanced Design System offers an extensive set of example projects that demonstrate designing for various technologies. You can view example projects, as well as copy and modify them to create new projects.

To view an example project choose File > Example Project and use the Open Example Project dialog box to select the directory and the project.



To copy an example project choose File > Copy Project , click the Example Directory button, and use the dialog box to locate and copy the project.



## Using Designs

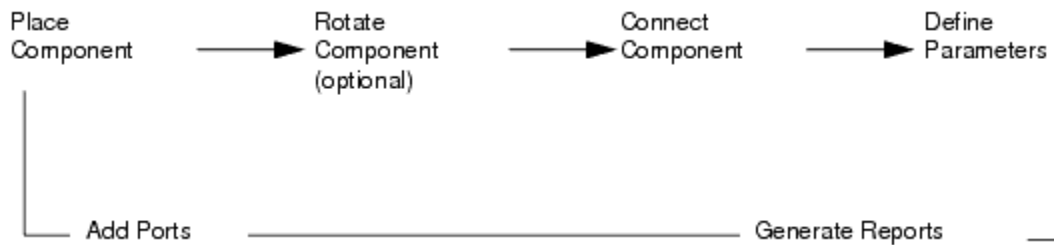
Advanced Design System uses designs to store the schematic and layout information you generate to accomplish your design goals.

A design can consist of a single schematic or layout, or it can be made up of a number of schematics and layouts embedded as subnetworks within a single design. All designs in a project can be displayed and opened directly from the Main window or from within a Design window.

In a Design window you can...

- Create and modify circuits and layouts
- Add variables and equations
- Place and configure components, shapes, and simulation controllers
- Specify layer and display preferences
- Include annotations using text and illustrations
- Generate layouts from schematics (and schematics from layouts)

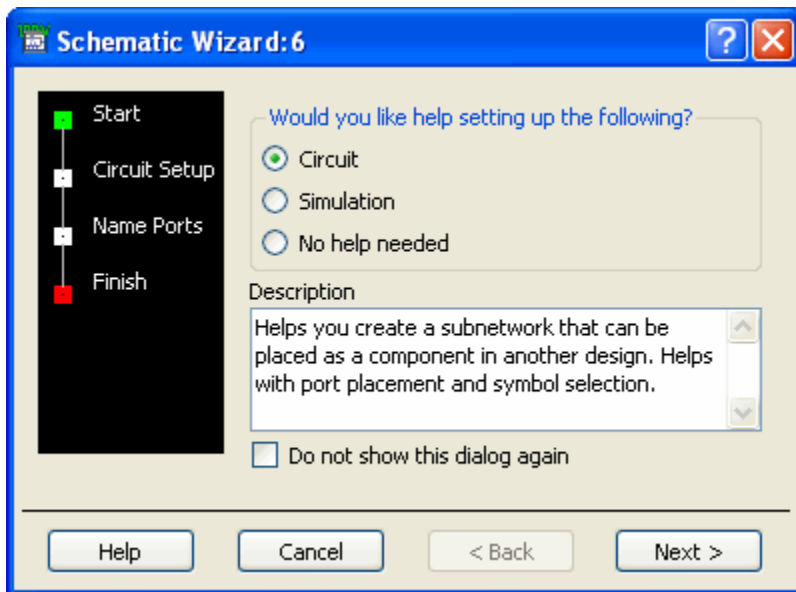
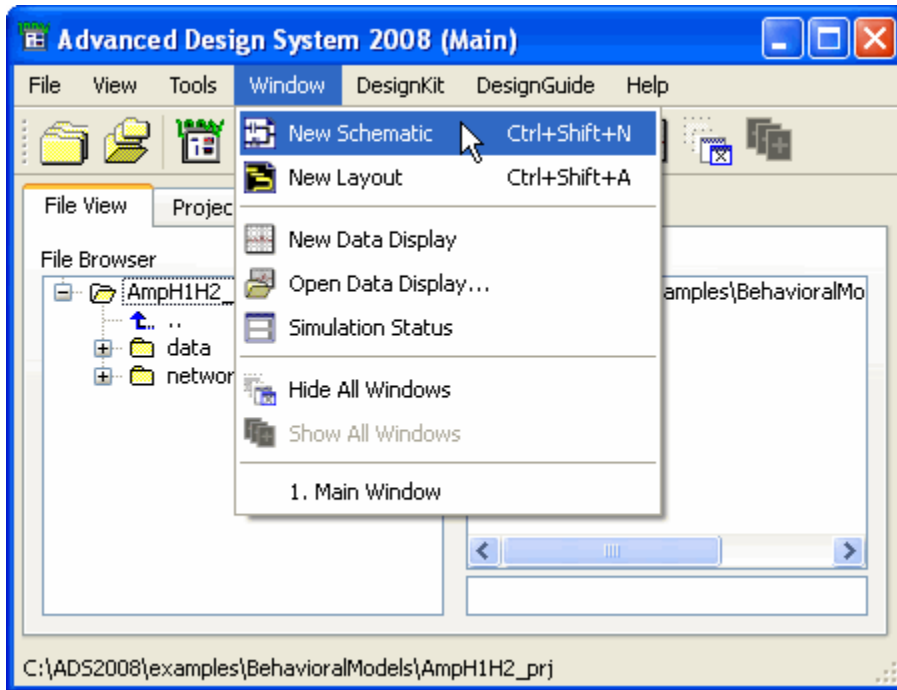
The basic process of creating a design or layout is as illustrated:



## Creating Designs

You can create a new design (layout) using one of three ways:

- Choose Window > New Schematic in the Main window and use the Schematic Wizard to set up a design.



- Choose Insert > Template in the Schematic window and select a template for the new file. When you use a template, most of the initial setup and configuration for the schematic, the simulation, and the data analysis is done for you automatically.
- Choose File > New Design in the Schematic (Layout) window and use the New Design dialog box to name the file you are creating. You can also open the Schematic Wizard or choose a Schematic Design Template from this dialog box.

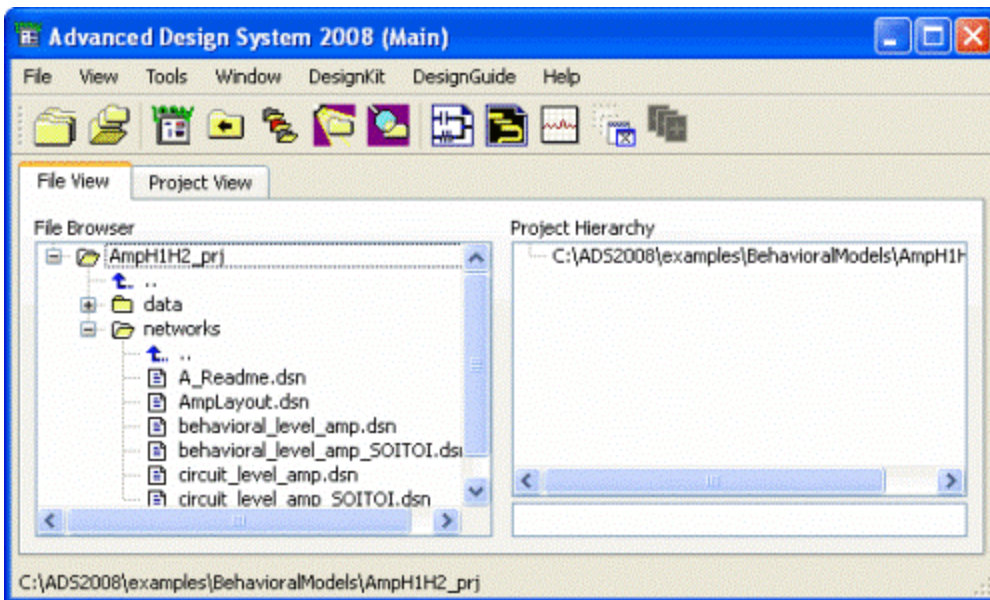
## Listing Designs

## Advanced Design System 2008

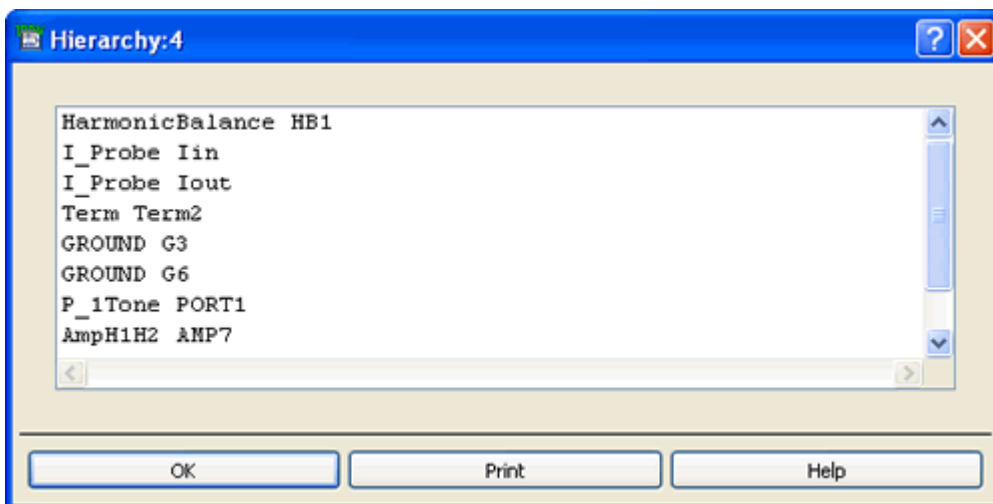
Even after you close all Schematic and Layout windows, designs that you opened remain in memory until you explicitly clear them or exit the program.

To list designs, use one of two ways:

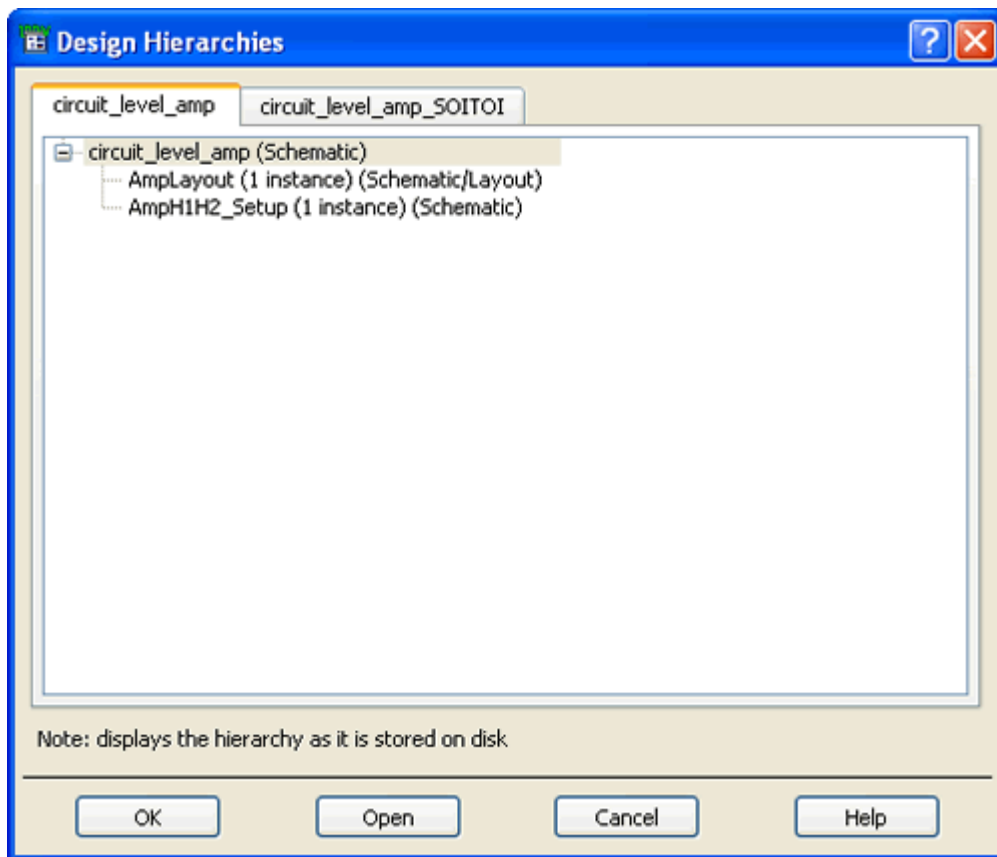
- In the Schematic (Layout) window, choose Window > Designs Open.
- In the Main window, double-click the Networks directory to display all designs, and then double-click a design to list its schematic, layout, and hierarchical information.



To view the component hierarchy within a design, choose Tools > Hierarchy from the schematic window.



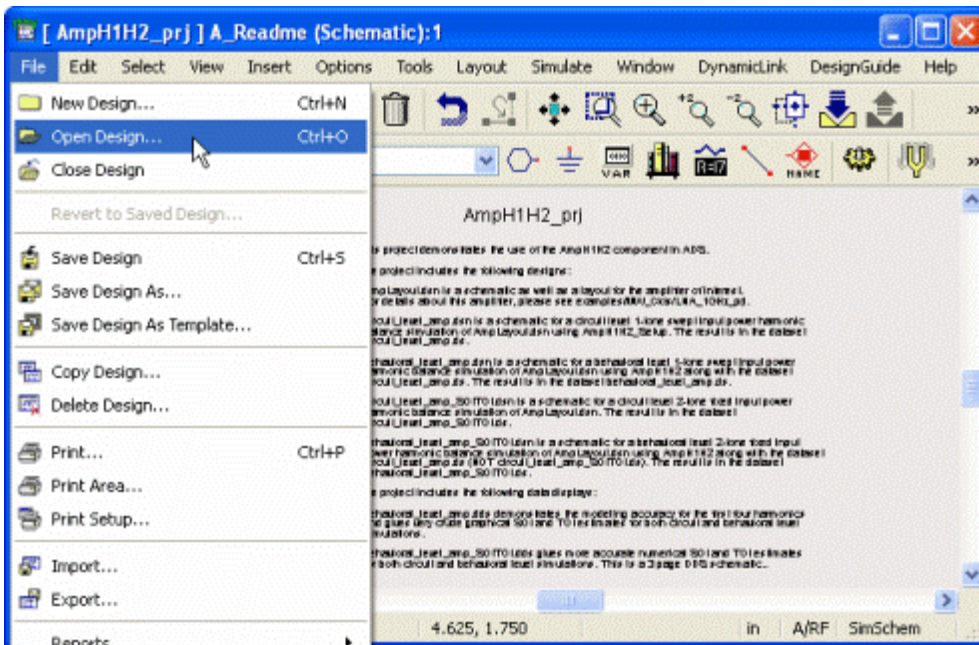
To view the design hierarchies within a project, choose View > Design Hierarchies from the Main window.



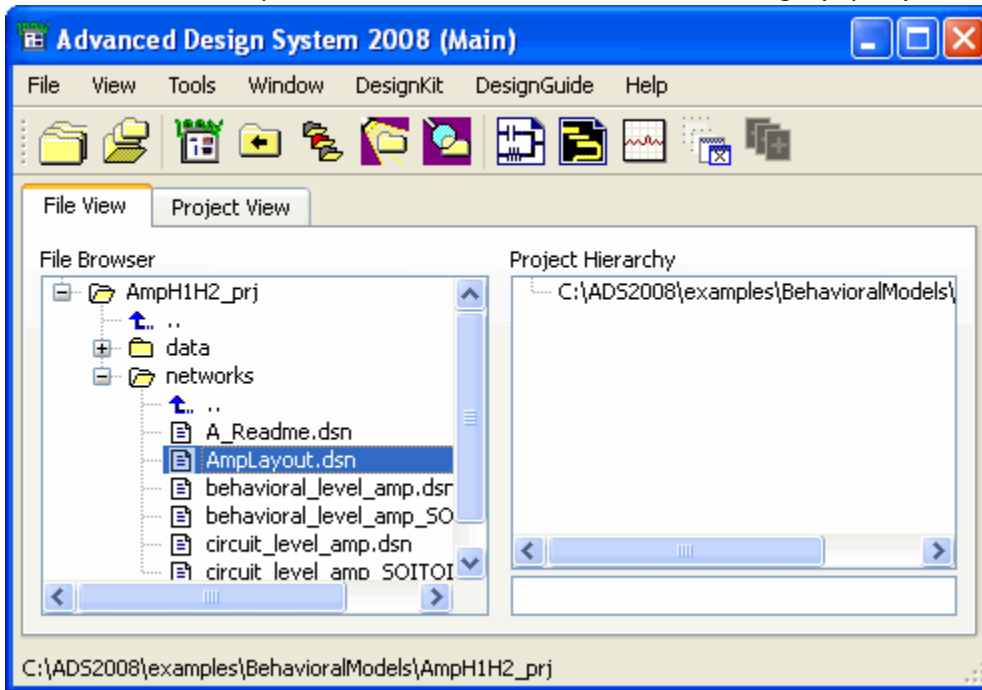
## Opening Designs

You can use either the Main window or the Schematic (Layout) window to open a design (layout).

- Choose File > Open Design in the Schematic (Layout) window and use the dialog box to locate and open the design.



- Use the File Browser pane of the Main window to locate the design (layout) and double-click to open it.



## Using Design Kits

To effectively use the design environment in Advanced Design System and take advantage of its powerful simulation

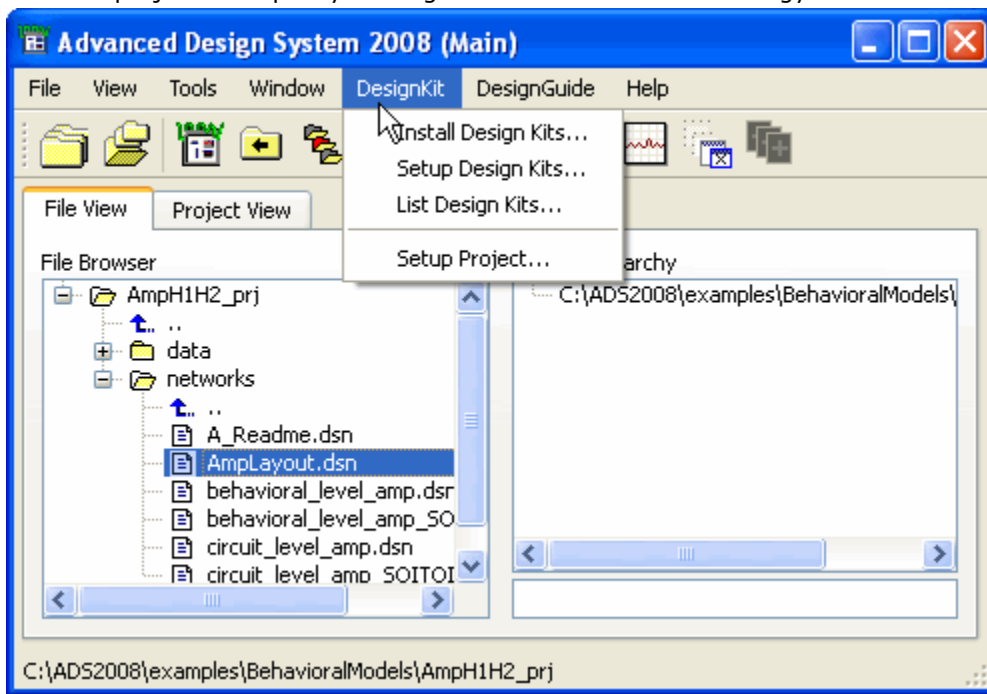
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capabilities, designers must have a library of components that are linked to model files or simulation data. These components and models are often distributed by foundries in the form of design kits. Many customers are also creating design kits themselves.

Agilent Technologies provides ADS design kits to popular foundries, for distribution to their customers. The ADS library structure can be used for any technology or process to package and distribute a reusable set of components. With the ADS Design Kit user interface, you can now easily install and manage all of your design kits.

From the ADS Main window, you can:

- Install a design kit
- Setup the design kit installation at different levels
- List multiple design kits simultaneously
- Define a project and specify a design kit to be used for technology files



Once your design kit is installed and configured, you can start using it just like any other ADS component. For more detailed information on ADS design kits, refer to the [Design Kit Installation and Setup](#) documentation.

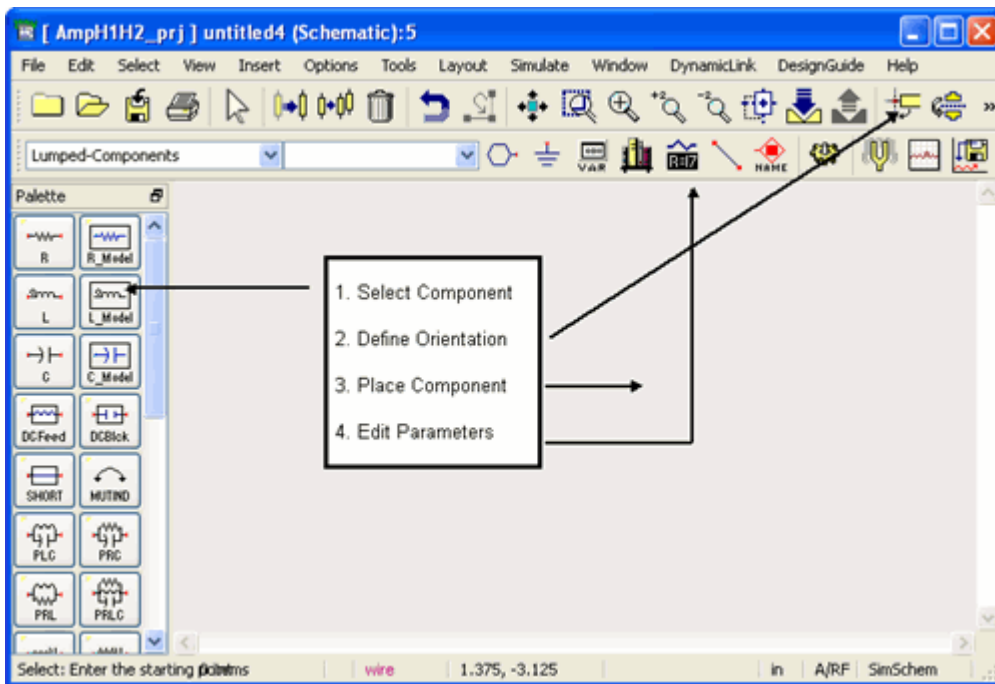
## Adding Components

You can place, connect, and configure the following items in the drawing area of your design window to create your design:

- Components
- Data items
- Measurement sources
- Simulation controllers

You can also add entire circuits as subnetworks to create hierarchical designs. Keep in mind that when you begin a design using a template, most of the simulation and analysis setup and configuration is done for you automatically.

To add a component...

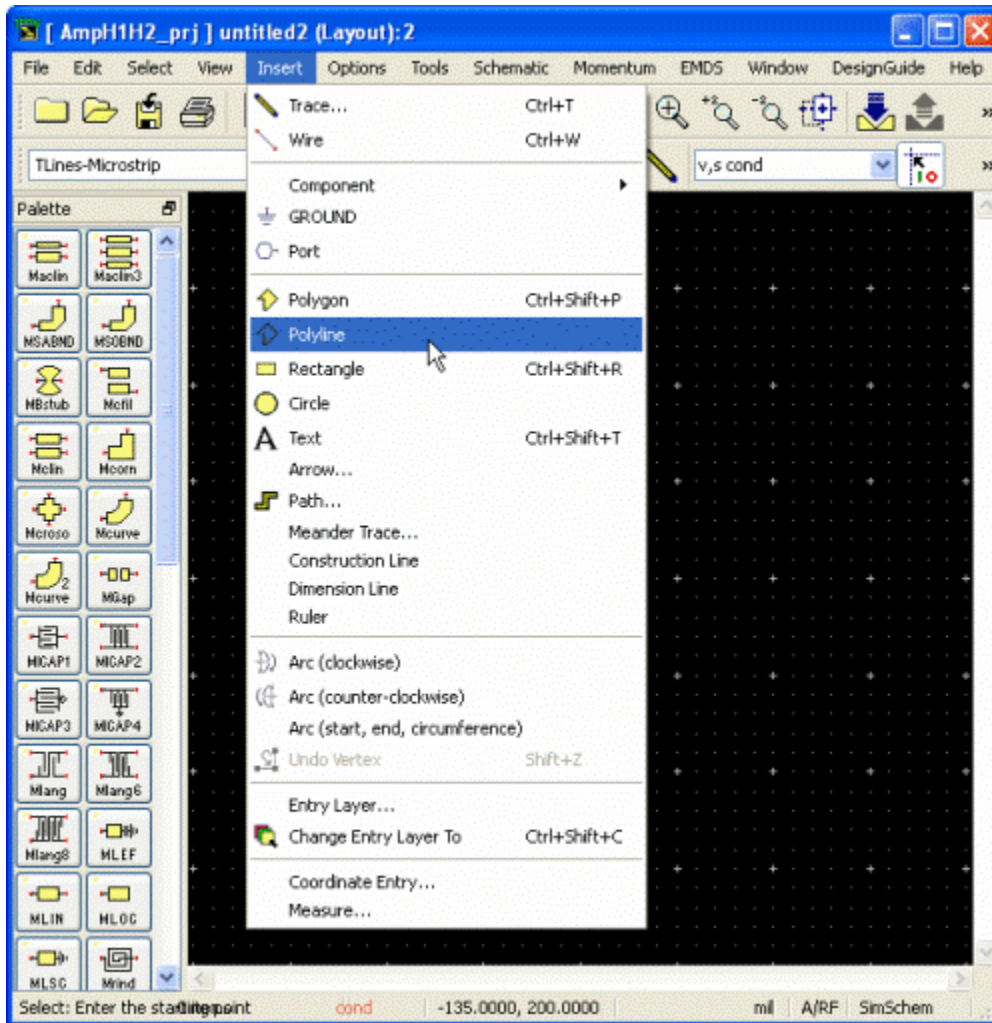


## Drawing Shapes

You can draw and modify shapes in the drawing area of your design window to create a layout. You can also add Traces to represent electrical connectivity.

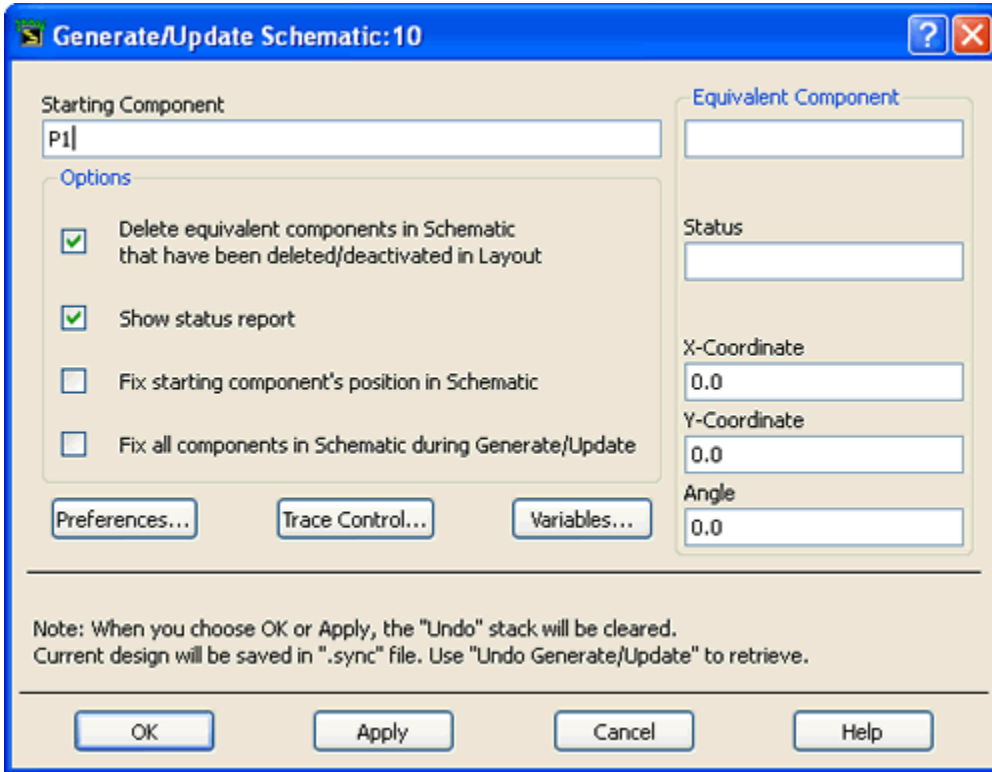
To place a shape...

1. Select the shape name from the Insert menu or click the shape on the toolbar.
2. Place the shape in the Layout window following the instructions that appear in the status bar at the bottom of the window.



## Synchronizing Designs

Use Design Synchronization (Schematic window > Layout > Generate/Update Layout OR Layout window > Schematic > Generate/Update Schematic ) to generate and synchronize your schematic and layout artworks and symbols. The window where you invoke the synchronization operation acts as the source from which the destination representation is generated or updated.



## Synchronization Modes

The synchronization can be complete or incremental and can be done to and from a schematic and a layout.

Generate	Update	Place Component
Place all activated components, including those with no artwork, connected to the starting component.	Update a previously generated design by placing components that have been modified	Place items that have no counterparts in the other representation.
Components with fixed location status are not moved.	Components with fixed location status are not moved.	Use the "Current Rep only" component placement mode.
Components that are not placed in the other representation are highlighted		"Wire guides" show connectivity in the other representation
Any component can serve as the starting point for which the location, orientation can be specified		Use the "Options > Variables" command to override the default resolution path for variable- and substrate- references

### Cross-Probing

To see the layout representation of a specific wire or pin in your schematic, select Layout > Show Equivalent Node and click the wire or pin that you would like to see in the layout. When you view the layout, the wire or pin that you selected in the schematic will be highlighted in red.

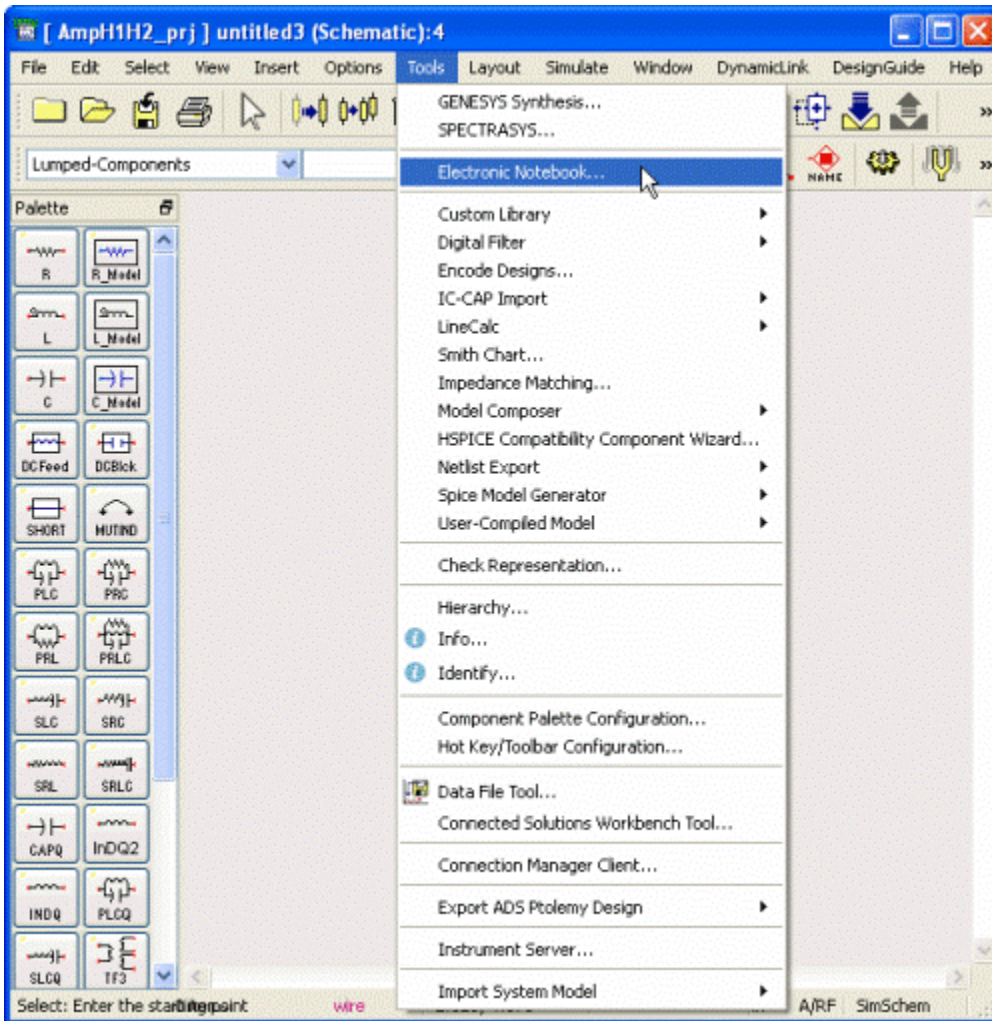
To see the schematic representation of a specific wire or pin in your layout, select Schematic > Show Equivalent Node and click the wire or pin that you would like to see in the schematic. When you view the schematic, the wire or pin that you selected in the layout will be highlighted in red.

### Documenting Designs

Advanced Design System includes a documentation tool for creating HTML documents using the designs and results within a project. This "Electronic Notebook" generation tool can be used to:

- Capture schematic, layout, and data display images in a project, and import images from other sources.
- Generate html documentation that can be distributed and viewed outside of ADS.

To document designs...



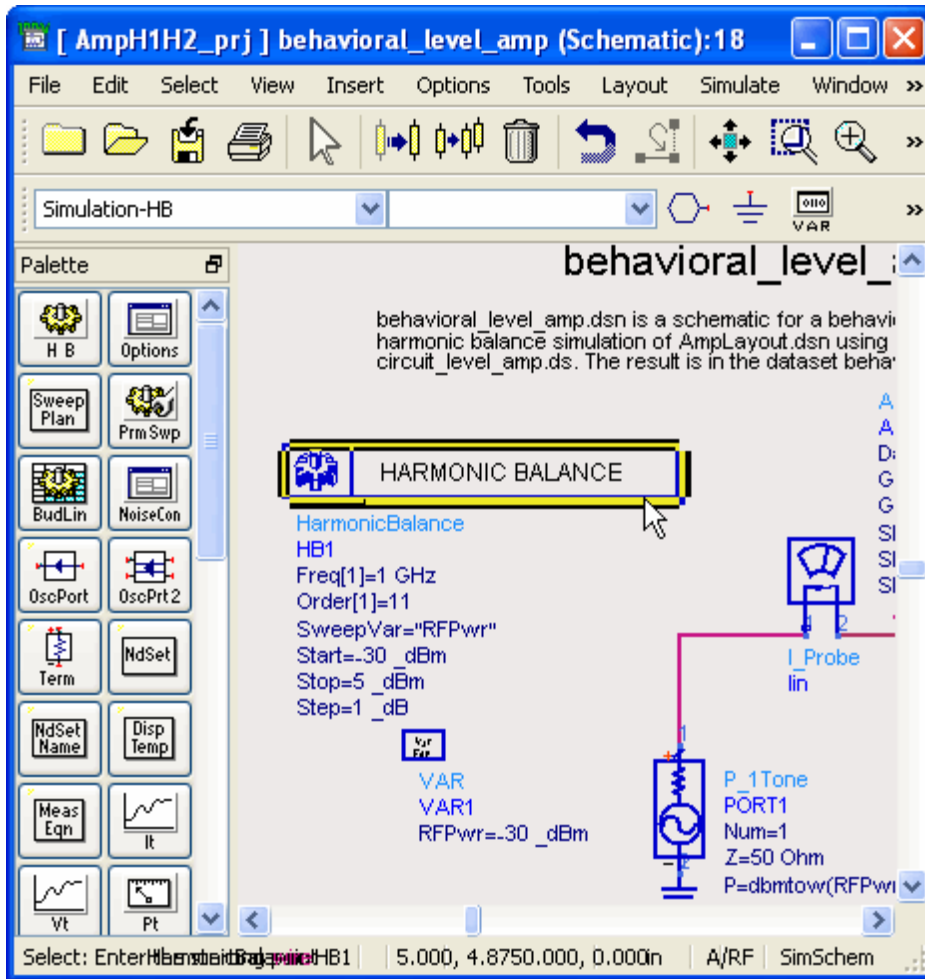
## Simulating Designs

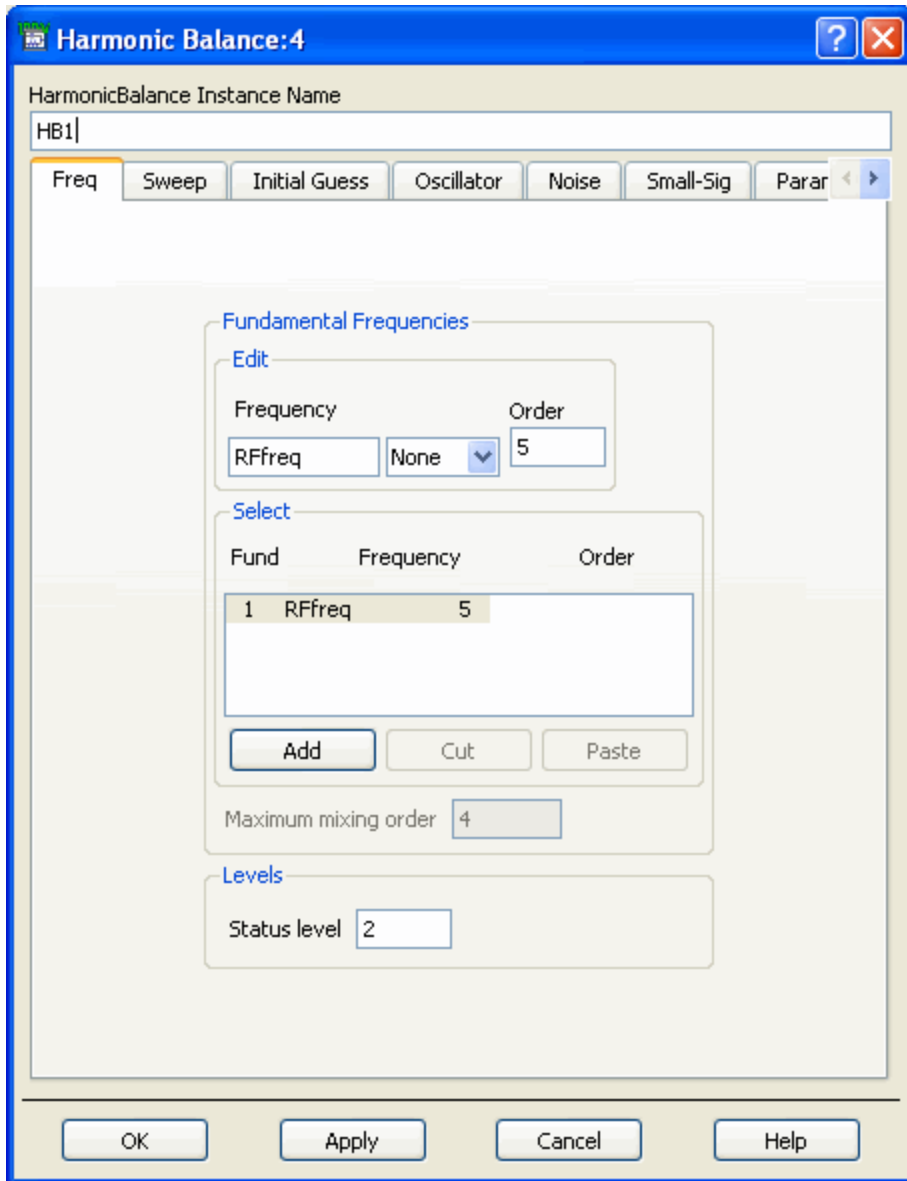
Advanced Design System provides controllers that you can add and configure to simulate, optimize, and test your designs.

A DSP design simulation requires a Data Flow Controller while an Analog/RF design simulation requires one or more of various controllers. You can either add and configure the appropriate controllers or you can insert a template (choose Insert > Template from a Schematic window) that contains the appropriate controllers.

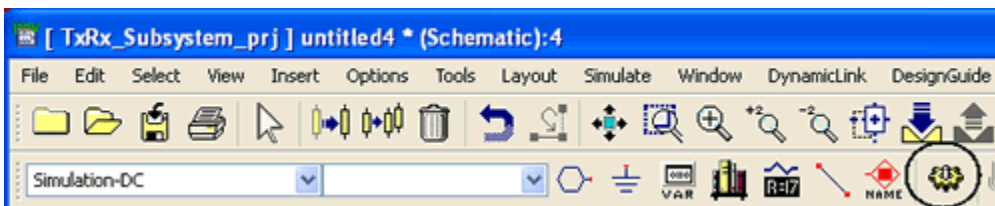
To simulate a design...

1. Click and place controller
2. Double-click to edit parameters

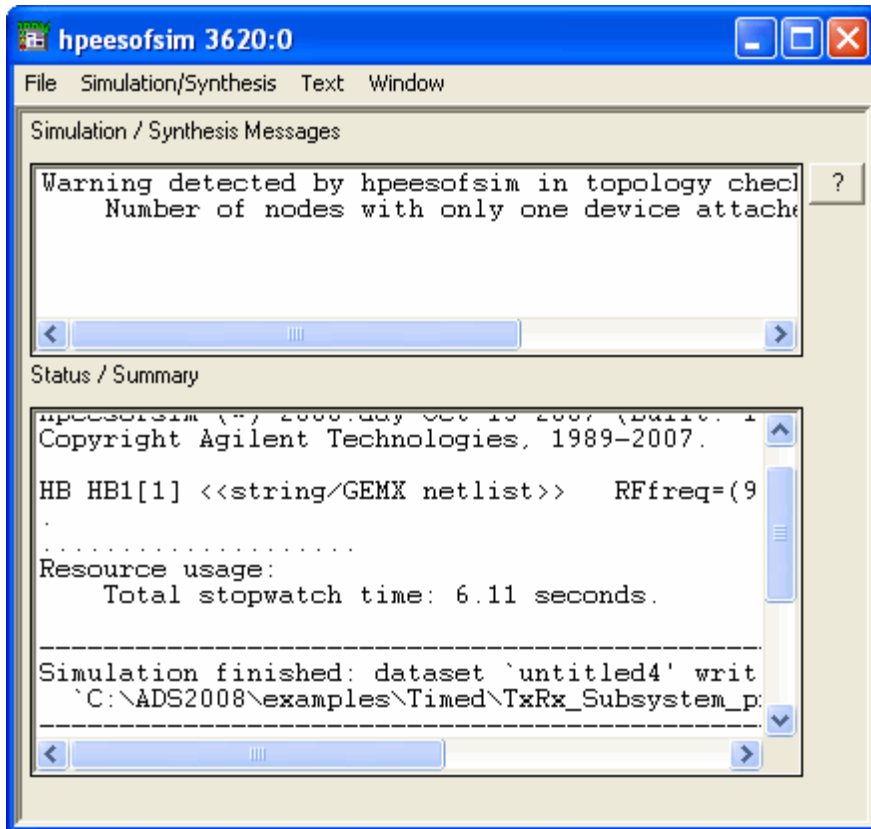




3. Click to simulate design



The status of the simulation is displayed in a message window.



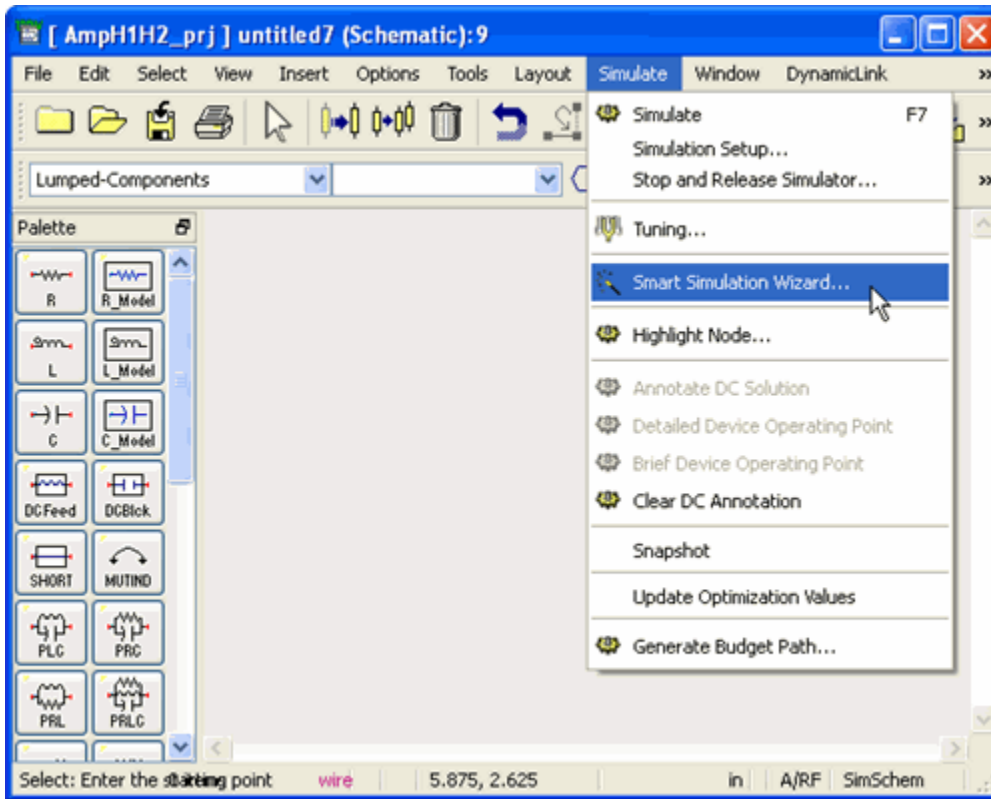
## Simulation Wizard

Advanced Design System also provides a step-by-step interface for circuit simulation. The Smart Simulation Wizard can be used to:

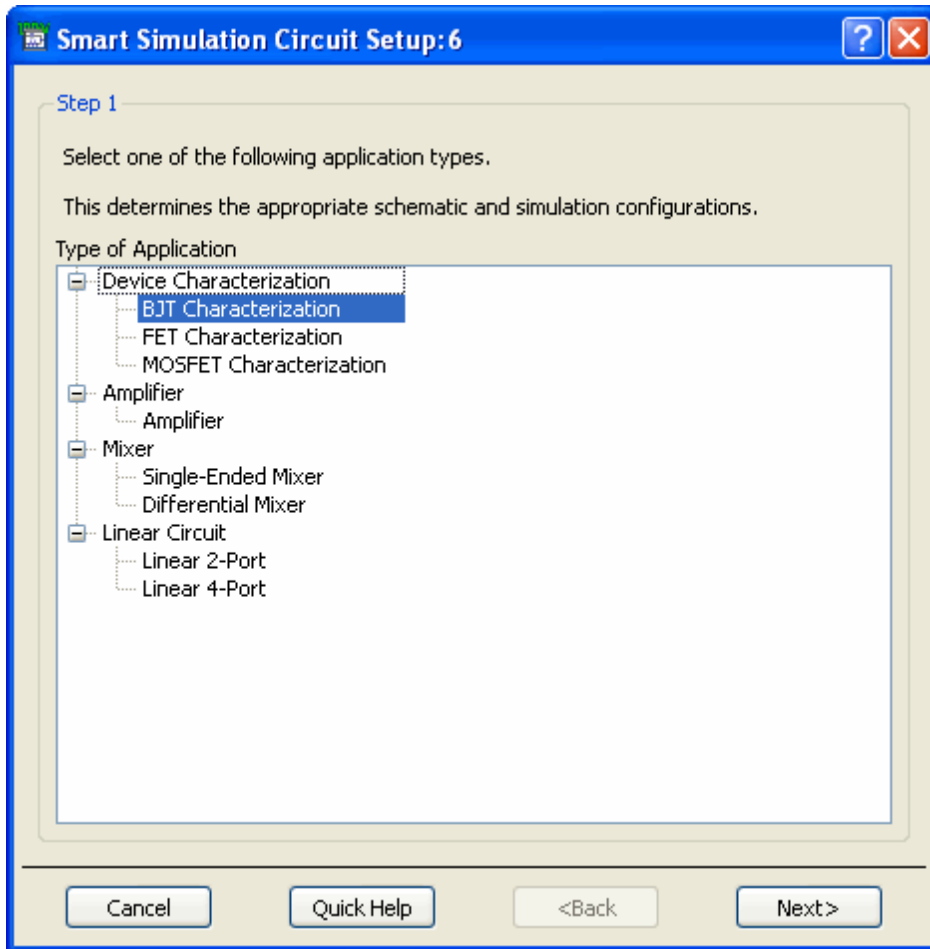
- Create Analog/RF designs
- Set up and run simulations
- Display simulation results

To "smart" simulate a design...

1. Choose Simulate > Smart Simulation Wizard



2. Specify Circuit Configurations



3. Specify Simulation Options
4. Display Results

## Signal Processing Simulation

ADS provides an integrated environment for the design and validation of RF/analog/DSP system designs to the implementation level using the ADS Ptolemy simulator. The ADS signal processing environment enables:

- Accurate RF system models for faster development of system specifications.
- Extensive behavioral model set for RF system and DSP system modeling that helps engineers rapidly create and optimize larger designs.
- Co-design between DSP, analog and RF portions of the signal path.
- Hundreds of DSP and analog models for development of algorithms.
- Propagation and matrix models that allow modeling of complete wireless systems.
- Data export and import capability to measurement instrumentation helps verify designs using virtual prototyping concepts.
- IP reuse of MATLAB, HDL, & C++ models.

The systems designer can architect a communications system using behavioral models to validate a concept. The

## Advanced Design System 2008

designer can then design and substitute lower levels of abstraction to verify the RF/mixed signal design down to the circuit level, and export the design to a variety of manufacturing tools. Available statistical design capability allow the user to make difficult trade-offs during the design process in order to optimize performance or manufacturing yield.

A large array of behavioral RF/analog/DSP models work with the ADS Ptolemy simulator to provide leading-edge simulation accuracy during the design process. The inclusion of propagation and matrix models, facilitate modeling of the complete wireless system. ADS communications library modules support the latest communications standards such as WLAN, 3GPP, and Edge. These libraries can be used at the front end of the design process when the system architecture is conceptualized, during the design and implementation process, or at the back end of the design process during the final verification.

Instrument links to Agilent Technologies test and measurement instrumentation products provide virtual prototyping verification for designs prior to final implementation or tape out. For example, a new RF/analog/DSP transmitter design modeled in the signal processing schematic can be verified by linking the output of the simulation with one of the Agilent ESG signal generator products. The resulting real world signal produced in a virtual environment will include all of the signal distortions, noise, and propagation effects modeled into the design. This signal can then be fed into an Agilent signal analysis component or real-world receiver circuit to provide virtual prototyping capability, and the ability to "tune" the design using real-world hardware and analysis.

ADS Ptolemy simulation is controlled using a [Data Flow Simulation Controller](#), sources, and sinks placed on the design. There must be at least one source or sink that is controlling the simulation. Controlling sinks and sources keep the simulation running; non-controlling sinks and sources do not.

### Sources

Sources are components with no inputs. Sources can read data from files, instruments, and data sets. When a source is controlling the simulation, it will keep the simulation running long enough to output all its data.

### Sinks

Sinks are components with no outputs. When a sink controls the simulation, it will keep the simulation running long enough to satisfy its start and stop times. When a sink is not controlling the simulation, it will start collecting data at Start, then collect as much data as the simulation produces.

### Components

There are two basic types of Ptolemy components "Timed" and "Numeric". Timed components have a notion of sampling rate, carrier frequency, and envelope. Numeric components process integers, matrixes, floats, fixed point numbers and model the DSP portions of a design.

For more information on...

- Cosimulation with analog/RF designs, refer to the [ADS Ptolemy documentation](#).
- Connecting to instruments, refer to the [Connection Manager documentation](#).
- Cosimulation with MATLAB IP import, refer to the [MATLAB Cosimulation documentation](#).
- Cosimulation and HDL IP import, refer to the [HDL Cosimulation documentation](#).
- C++ IP import, refer to the [Model Builder documentation](#).

### Analog/RF Simulation and Convergence

Analog/RF simulation computes the response of a circuit to a particular stimulus by formulating a system of circuit equations and then solving them numerically. Each simulation technology accomplishes this analysis as follows.

#### DC Analysis

- Solves a system of nonlinear ordinary differential equations (ODEs)
- Solves for an equilibrium point
- All time-derivatives are constant (zero)
- System of nonlinear algebraic equations

#### Transient Analysis

- Solves a system of nonlinear ordinary differential equations (ODEs)
- Time-derivatives replaced with a finite-difference approximation (integration method)
- Sequence of systems of nonlinear algebraic equations (one system at each timepoint)

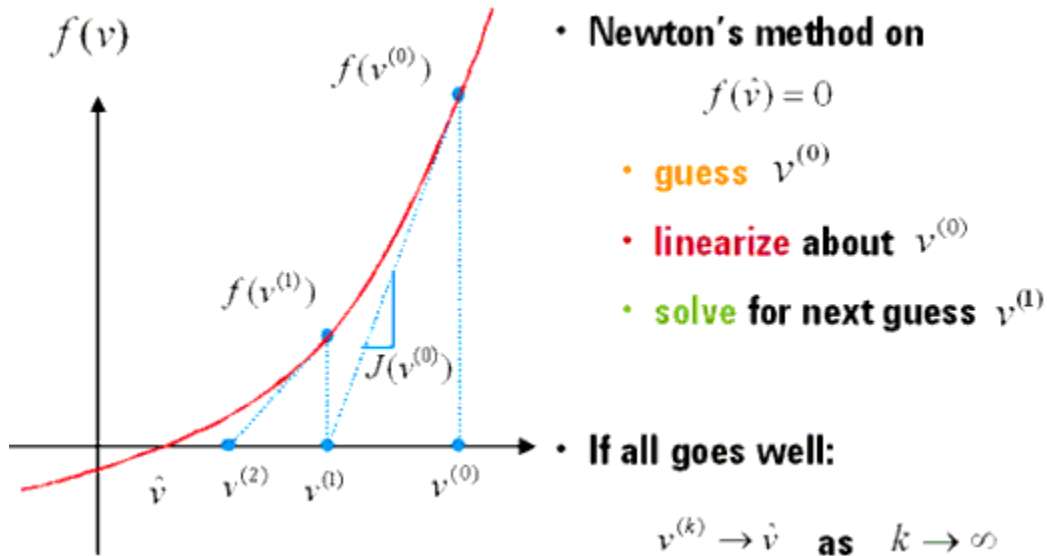
#### Harmonic Balance (HB)

- Solves a system of nonlinear ordinary differential equations (ODEs)
- Steady-state method
- Solution approximated by truncated Fourier series
- System of nonlinear ODEs becomes a system of nonlinear algebraic equations in the frequency domain

#### Solving Nonlinear Algebraic Equations

Nonlinear algebraic equations are solved using the Newton-Raphson algorithm (Newton's method) as follows.

- Convert the problem to a sequence of systems of linear equations
- Quadratic convergence near the solution (error squared at each iteration)



## S-parameter Test Lab

An S-parameter test lab enables you to calculate the S-parameters of multiple N-port networks in a single simulation run.

An S-parameter test lab is a schematic that contains one S-parameter test lab component and one or more test benches. A test bench is a schematic that contains an N-port network and terminations for each port of the network. Its use is best illustrated in multiple stage circuit designs where viewing the inter-stage circuit behavior of all stages simultaneously is desired. In such situations the S-parameter test lab can be used to terminate each stage in the applicable input/output impedances of adjacent stages rather than in the standard 50 ohms.

RefNets can also be used in conjunction with the S-parameter test lab feature.

## Design Sequencer

A Design Sequencer controller enables you to sequence multiple simulations in a single simulation run using a test bench that includes all the desired simulation controllers and the top-level design file. Some typical applications for a Sequencer controller are as follows.

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- Optimizing a variable across multiple simulations
- Enabling complex instrument control in Ptolemy
- Running a series of verifications tests on a design

### Differences Between S-parameter Test Labs and Sequencer

Sequencer	Test Lab
DC, SP, AC, HB, Tran, ENV, Ptolemy	SP only
Utilizes Test Bench Controllers	Utilizes Test Lab Controller
Different temps per test bench possible	One simulation temp for all
Opt/Stat/ParamSwp at top level	
RefNets supported	

### RefNets

A RefNet (reference network) component enables the port impedance from another design file in the system (the referenced network) to be referenced as a terminating impedance for the current design file under test.

Two typical applications for RefNets are as follows.

- Inter-stage circuit analysis and design: In some design applications it is desirable to simultaneously evaluate the performance of individual circuit stages terminated in the input and output impedances of adjacent stages. To accomplish the termination of an individual stage referenced to a specific port of other stages in the design chain, the RefNet is utilized in the S-parameter test lab.
- Design specific termination: For some top level DC, AC, or S-parameter design files, it may be desired to terminate a port whose impedance is characterized by data, from an external file (e.g. S-parameters, Z-parameters, Y-parameters) or some other network.

The two RefNet components, RefNetTB and RefNetDesign, have the same functionality and are supported under DC, AC and S-parameter analysis, with two differences:

- RefNetTB supports nested network referencing while RefNetDesign does not.
- RefNetTB uses a test bench as the reference design while RefNetDesign uses a standard (non-test-bench) schematic design.

## Common Circuit Simulation Methods

### Backward Euler

- First order method that assumes the solution waveform is linear over one time step
- One-step method (needs one previous time point solution only)
- Adapts faster to abrupt signal changes
- Stable on all stable differential equations and some unstable ones.
- Exhibits heavy numerical damping, increases loss
- Require smaller time step to maintain accuracy

### Trapezoidal Rule

- Second-order method, assumes the solution waveform is quadratic over one time step
- One-step method
- May exhibit point-to-point ringing on circuits that have very small time constant comparing to time step (stiff circuit)
- Stable only on stable differential equations
- Exhibits no artificial numerical damping

### Backward Difference Formulas (Gear's methods)

- Multiple order polynomial over one time step
- Only the first six orders are available in ADS
- First order method is identical to backward Euler
- Higher-order polynomials allow a larger time step without sacrificing accuracy, are efficient for smooth waveforms
- Higher order methods (order  $> 2$ ) may exhibit stability problems on lightly damped circuits
- Second-order backward difference formula (Gear 2)
- Two-step method
- Stable on all stable differential equations and some unstable ones.
- Exhibit some numerical damping

### Truncation Error

The error made by replacing the time derivatives with a discrete-time approximation. This error is difficult to estimate and depends on the type of circuits and the time steps.

### Local Truncation Error (LTE)

The truncation error made on a single step

### Global Truncation Error (GTE)

- Maximum accumulated truncation error
- The circuit with long time constant is sensitive to these errors
- Logic and bias circuits are not sensitive to these errors

### Convergence Criteria

Newton's iteration is converged if the approximate solution first satisfies the Residue criteria at the end of each Newton iteration and the Update criteria once the residue criteria are satisfied.

### Residue Criterion

KCL satisfied to a given tolerance. This is enforced at each node and is important when impedance at a node is small.

### Update Criteria

Difference between the last two iterations must be small. This is important when impedance at a node is large.

## Using Continuation Methods

Use continuation methods to provide a sequence of initial guesses that are sufficiently close to the solution to assure Newton's method convergence.

- Choose a natural or contrived continuation parameter which controls a modification of the circuit
- Step the continuation parameter from 0 to 1 (the original circuit configuration), using the solution from the previous step as the starting point

As long as the solution changes continuously as a function of the continuation parameter and the steps are small enough, Newton's method will converge. Keep in mind though that the first two methods, Source and gmin stepping, will fail if the continuation path contains a limit point.

### Source Stepping

Uses a fraction of the source voltages and currents applied to the circuit as the continuation parameter.

- Turn off all sources when the continuation parameter equals 0
- Raise source levels to their final levels slowly, generating a sequence of circuit configurations
- Use the solution from the previous configuration as an initial guess for the current configuration

### Gmin Stepping

Uses the continuation parameter to control the value of the gmin resistors.

- Start with a large gmin for an easy to compute solution because nonlinear device behavior is muted by the presence of the small resistors
- End with very small gmins for resistors that are so large that they no longer affect the circuit
- Remove the gmins to compute the final solution

### Arc-length Continuation

Works best for complicated continuation paths and limit points using a continuation parameter that is a function of the arc-length parameter.

- Travel same distance at each step, as specified by the arc-length
- Increase or decrease the continuation parameter along the path in each step

### Preventing Convergence Problems

Convergence problems usually arise as a result of errors in circuit connectivity or unreasonable (out of range) model or component values. Some of the steps you can take are as follows.

- Turn on the topology checker
- Turn on warnings
- Act upon the messages in the ADS Status Server window
- Eliminate small floating resistors (or increase I\_AbsTol) because any error in computed voltages for nodes with small resistors results in large error currents
- Avoid very large and very small resistances connected to a node because large resistances are lost during Jacobian construction due to numerical round-offs

## Momentum Simulation, Optimization, and Visualization

Momentum includes simulation, optimization, and visualization tools for predicting the performance of multilayer high-frequency circuit boards, antennas, hybrids, multichip modules, and integrated circuits.

Momentum enables you to:

- Simulate when a circuit model range is exceeded or the model does not exist
- Identify parasitic coupling between components
- Go beyond simple analysis and verification to design automation of circuit performance
- Visualize current flow and 3-dimensional displays of far-field radiation

Momentum is an electromagnetic simulator that computes S-parameters for general planar circuits, including microstrip, slotline, stripline, coplanar waveguide, and other topologies.

Momentum Optimization varies geometry parameters automatically to help you achieve the optimal structure that meets the circuit or device performance goals.

Momentum Visualization provides a 3-dimensional perspective of simulation results, enabling you to view and animate current flow in conductors and slots, and view both 2D and 3D representations of far-field radiation patterns.

## Instrument Connectivity

Connection Manager enables the sharing of signals, measurements, algorithms, and data between ADS simulations and Agilent instruments (signal generators and signal analyzers).

Using Connection Manager, you can:

- Access and control instruments from ADS dialogs
- Measure devices and construct ADS data sets from the measurement data
- Create simulation models based on measured data
- Use real-time instrument-generated stimulus and measurement during simulations

## Simulation Controllers

Add one or more simulation controllers to the design based upon the type of design to be simulated and the kinds of analyses desired.

Description	Typical Use
<a href="#">Data Flow Simulation Controller</a> Controls the flow of mixed numeric and timed signals for	All signal processing designs

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digital signal processing simulations using the ADS Ptolemy simulator.	
<a href="#">DC Simulation Controller</a> Fundamental to all RF/Analog simulations. It performs a topology check and an analysis of the DC operating point.	All RF/Analog designs
<a href="#">AC Simulation Controller</a> Obtains small-signal transfer parameters like voltage gain, current gain, and linear noise voltage and currents.	Filter Amplifier
<a href="#">S-Parameter Simulation Controller</a> Provides linear S-parameter, linear noise parameters, transimpedance, and transadmittance. Can be used to achieve many goals of the AC simulator.	Filter Oscillator Amplifier
<a href="#">Harmonic Balance Simulation Controller</a> Uses nonlinear harmonic-balance techniques to find the steady-state solution in the frequency domain.	Mixer Oscillator Power Amplifier Transceiver
<a href="#">Circuit Envelope Simulation Controller</a> Uses a combination of frequency- and time-domain analysis techniques to yield a fast and complete analysis of complex signals such as digitally modulated RF signals.	Mixer Oscillator Power Amplifier Transceiver Phase-locked Loop
<a href="#">LSSP Simulation Controller</a> Performs large-signal S-parameter analyses to represent nonlinear behavior. The accompanying P2D simulator can be used to speed up subsequent analyses.	Power Amplifier
<a href="#">XDB Simulation Controller</a> Seeks a user-defined gain-compression point at which an actual power curve deviates from an idealized linear power curve.	Power Amplifier Mixer
<a href="#">Transient/Conv. Simulation Controller</a> Solves a nonlinear circuit entirely in the time domain using simplified models to account for the frequency-dependent behavior of distributed elements.	Mixer Power Amplifier Switching Circuits
<a href="#">RF Budget Controller</a> Determines the linear and nonlinear characteristics of an RF system made up of a cascade of two-port, two-pin linear or nonlinear components.	Mixer Nonlinear Amplifier

## Optimization & Statistical Design Controllers

## Advanced Design System 2008

Optimization and statistical design controllers are used in conjunction with RF/Analog and signal processing simulation controllers to:

- Characterize and improve an unknown process such as the response of a design
- Identify variables that contribute significantly to variations in performance
- Vary parameter values to identify combinations that deliver the desired yields

Some of their design applications include:

- Optimizing gain and matching
- Filter response optimization
- Pulse-rise time tuning
- Carrier lock time and residual loop error optimization
- Fixed-point bit-width optimization
- Maximize manufacturing yield

Advanced Design System includes the optimization and statistical design controllers shown below. For more detailed information on optimization and statistical design, refer to the [Tuning, Optimization, and Statistical Design](#) documentation.

Description	Used With
<p><a href="#">Nominal Optimization Controller</a> Used to compare computed and desired responses and modify parameter nominal values to bring the computed response closer to the desired optimization goals.</p>	<p>Goal Component (required) A Goal component is used in conjunction to specify the optimization goals.</p>
<p><a href="#">Monte Carlo Controller</a> Uses the Monte Carlo method to simulate a design over a given number of trials in which the statistical variables have values that vary randomly about their nominal values with specified probability distribution functions.</p>	<p>Yield Specification Component (optional) A Yield Specification component is used in conjunction to specify the desired yields. Statistical Correlation Component (optional) A Statistical Correlation component is used to specify statistical correlation between statistical design variables.</p>
<p><a href="#">Yield Analysis Controller</a> Uses the Monte Carlo method described above to determine the manufacturing yield. For each trial, the computed response is compared to the corresponding yield specification, and a pass/fail decision is made.</p>	<p>Yield Specification Component (required) A Yield Specification component is used in conjunction to specify the acceptable performance. Statistical Correlation Component (optional) A Statistical Correlation component is used to specify statistical correlation between statistical design variables.</p>
<p><a href="#">Yield Optimization Controller</a> Used to analyze multiple yield analyses and adjust the nominal values to maximize the yield estimate of the statistical design variables.</p>	<p>Yield Specification Component (required) A Yield Specification component is used in conjunction to specify the acceptable performance.</p>
<p><a href="#">Design of Experiments Controller</a> Used to sequentially and iteratively improve the statistical performance of a design by identifying variables that contribute significantly to performance variation and honing in on the target statistical response.</p>	<p>DOE Goal Component (required) A DOE Goal component is used in conjunction to specify the desired goals.</p>

## Analyzing Results

Advanced Design System uses datasets to store the simulation information you generate when analyzing designs. You can display this information for analysis using the Data Display window. A Data Display window can also be used to display data imported from other sources.

In a Data Display window you can:

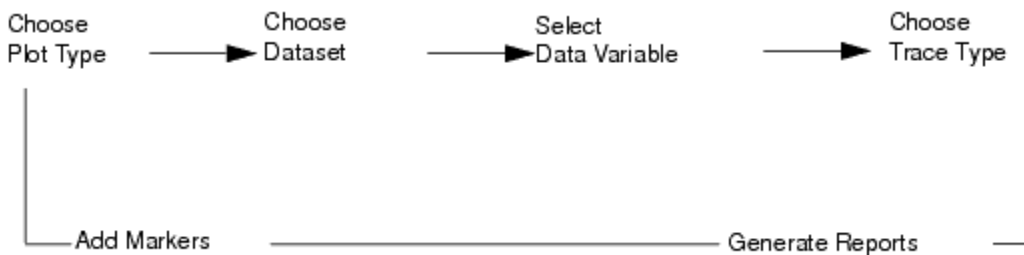
- Display data in a variety of plots and formats
- Use markers to read specific data points on traces
- Use equations to perform operations on data
- Annotate results using text and illustrations

Once a simulation is complete, the data is displayed automatically if you did one of the following (a blank Data Display window is opened if you did none of them):

- Specified a dataset and display before simulation
- Used a schematic template for an Analog/RF simulation
- Specified Rectangular in the Plot parameter in a sink for a Signal Processing simulation

## Creating Data Displays

The basic process of creating a data display is as illustrated:



1. Choose a plot type for the display
2. Choose the dataset that contains the data you want to display
3. Select the data variable to be displayed
4. Choose a trace type for the display

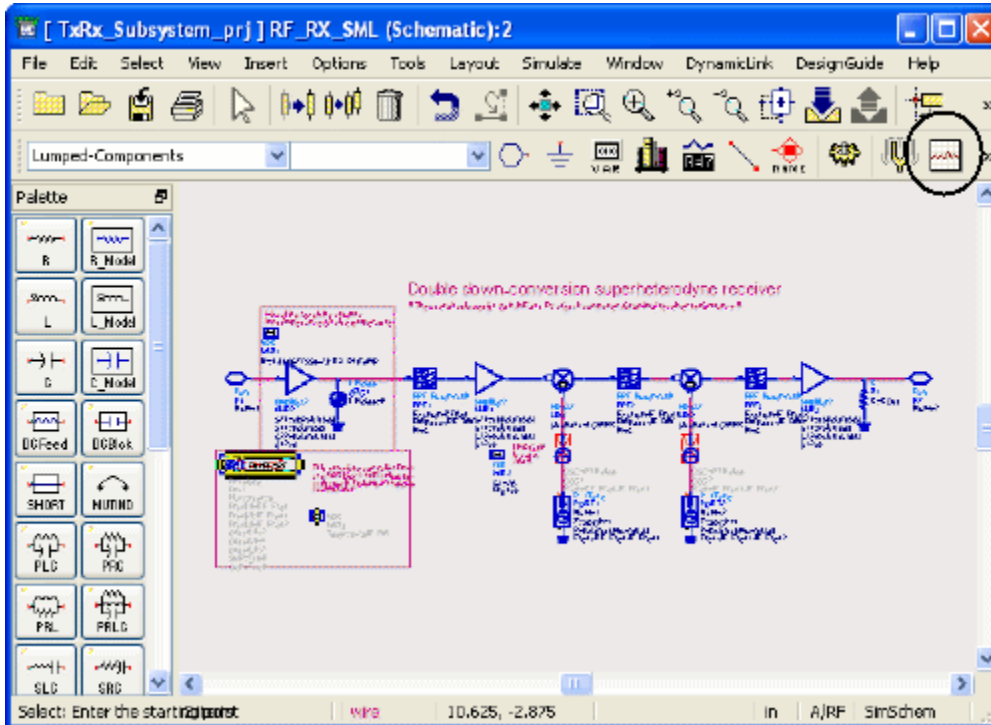
To enhance the display you can also add:

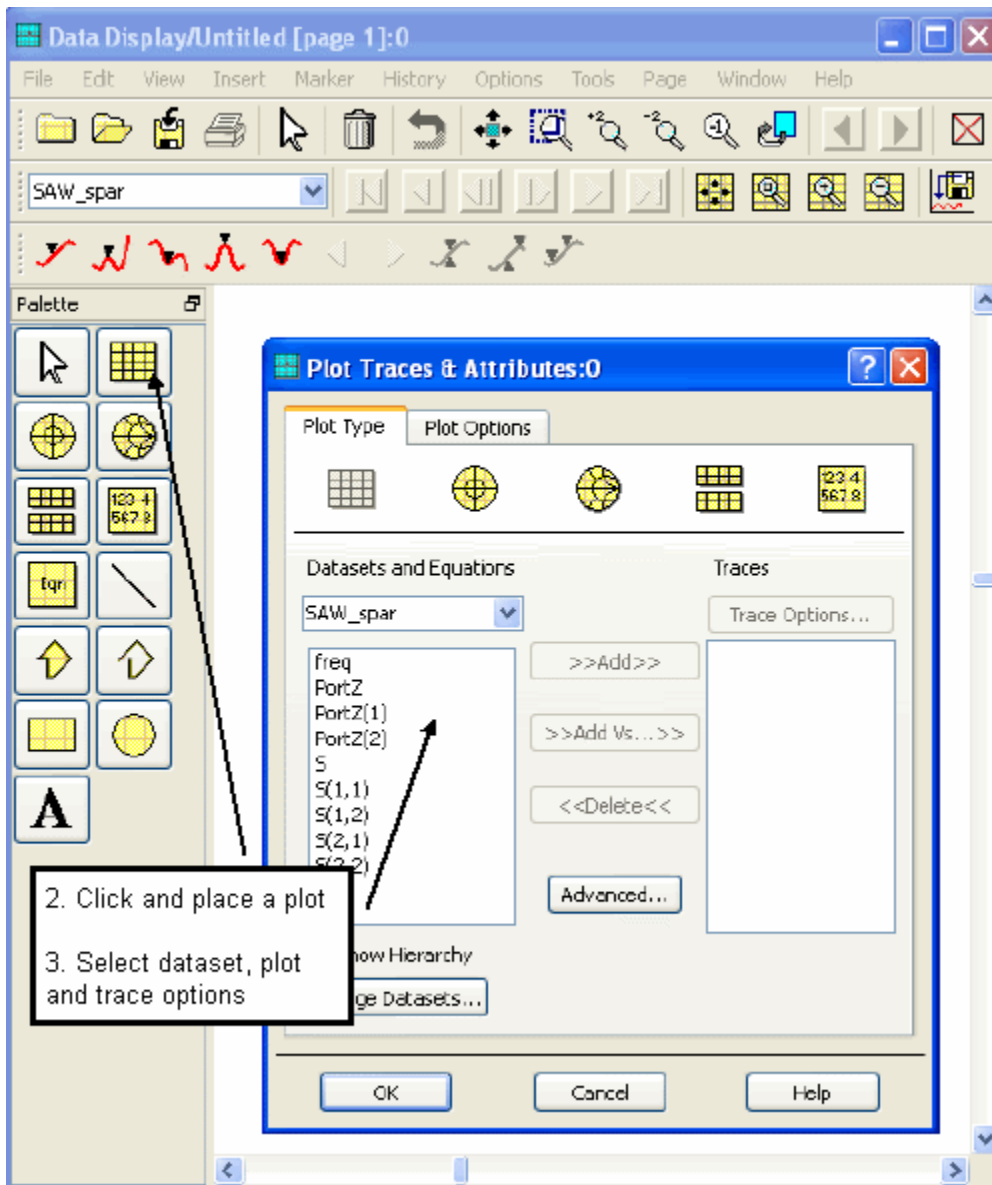
- Markers to identify specific data points
- Annotations using text and illustrations
- Legends to help identify specific traces

If you used a template to create the design you have simulated, the initial setup and configuration to create displays for data analysis is done for you automatically.

To create a data display...

1. Click to open a data display





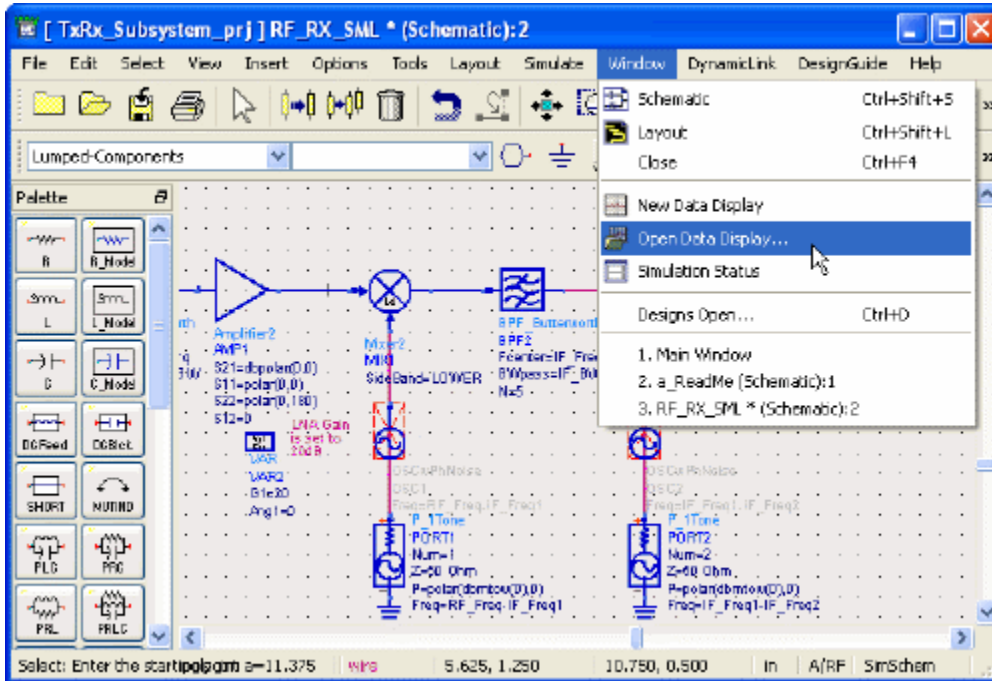
## Viewing Results

To view simulation results from the Main, Schematic, or Layout window choose Window > Open Data Display and use the dialog box to locate and open the results.

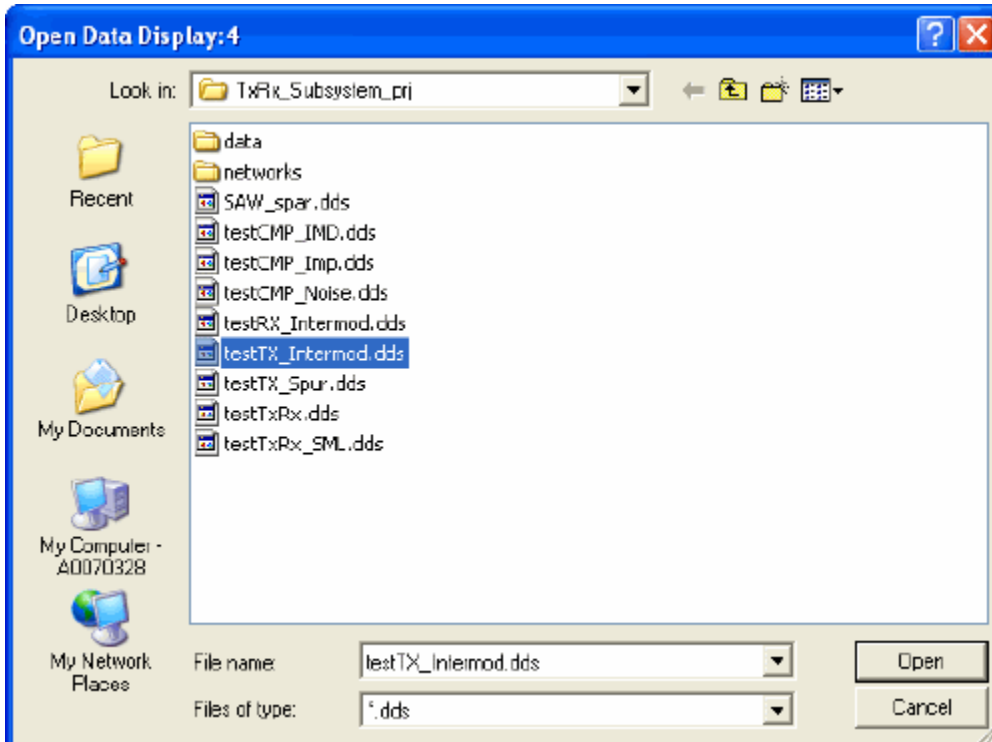
**i** To display a list of data display files in the File Browser pane of the Main window you will need to be sure the Show All Files option ( View > Show All Files ) is selected.

To display simulation results...

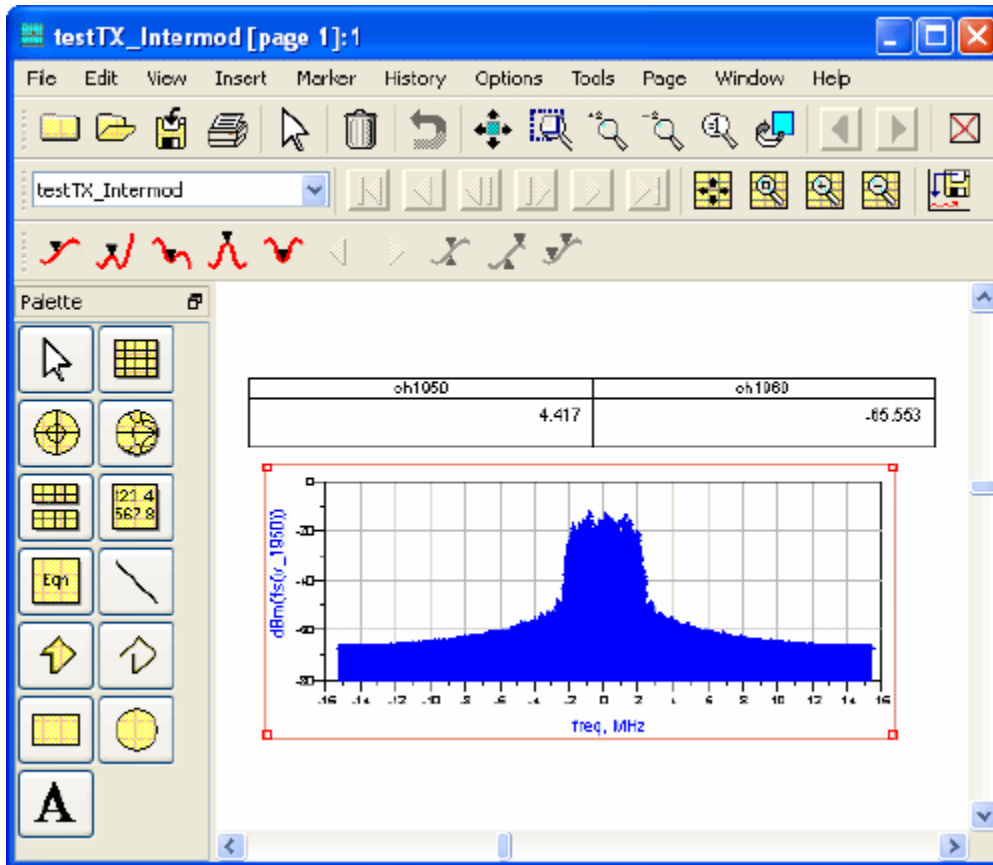
1. Open Data Display Window



2. Select Dataset File



3. Display Simulation Results



## Display Options

The following plot, trace, and data options can be used to display data for analysis:

Plot Type	Trace Type	Data Source
Rectangular plot Stacked plot Smith chart Polar plot	Auto Bus Linear Scatter Spectral Histogram Digital Sampled	Simulation dataset File Formats - Touchstone - MDIF - Citifile - ICCAP
List		

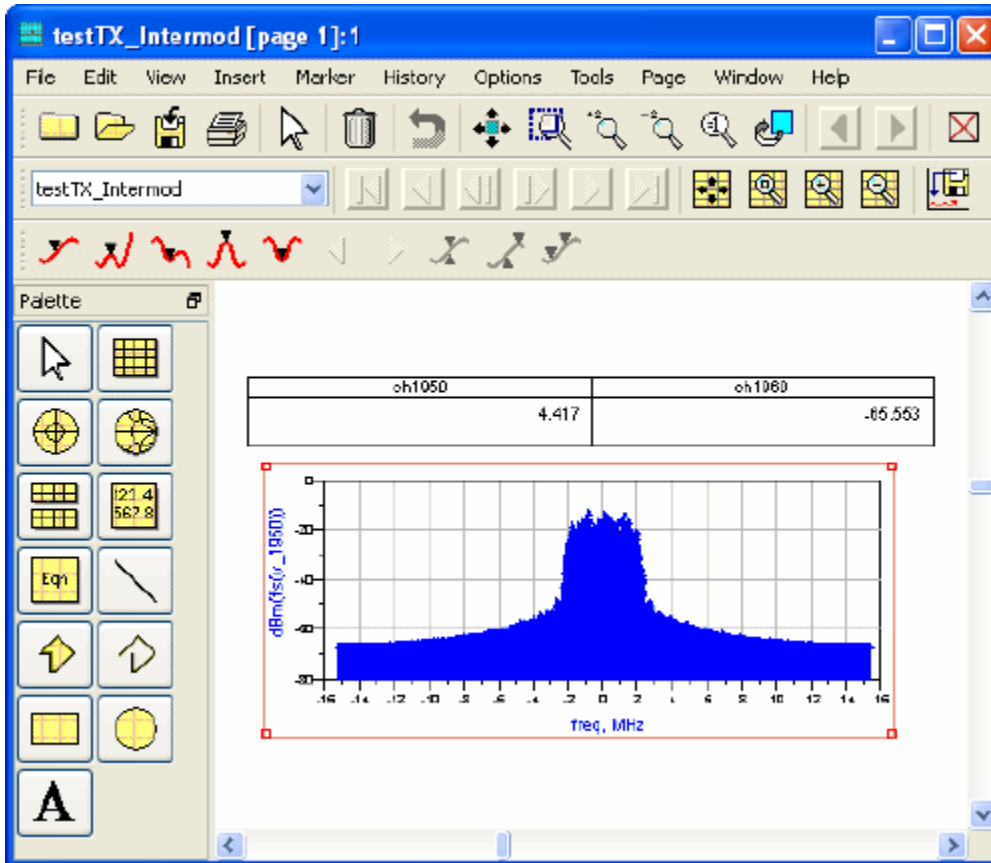
## Using Functions

You can use Measurement Equations to perform operations on data generated during a simulation. These equations are created using functions that are based on AEL, the Application Extension Language.

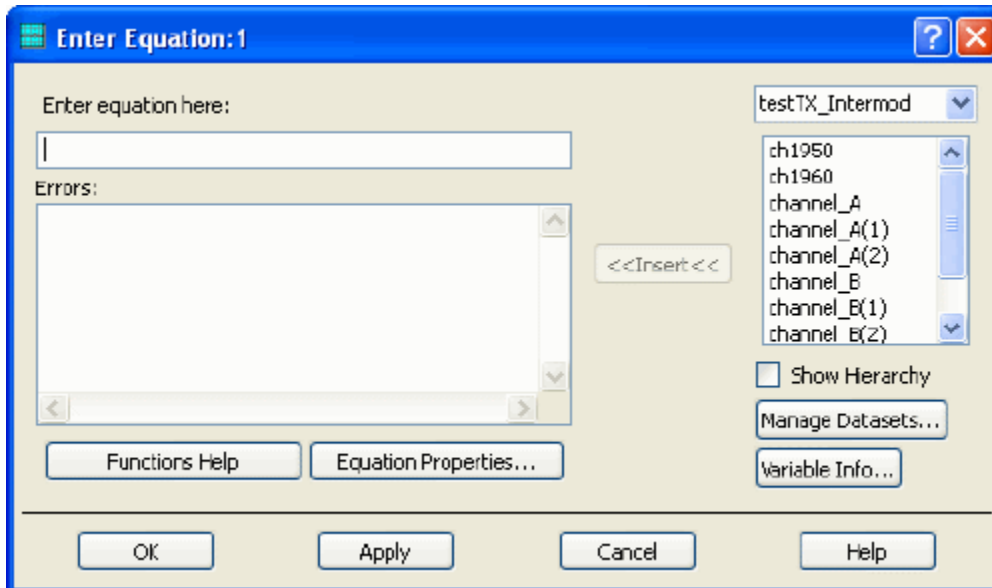
**i** Note Data from a marker can also be used as part of an equation. To insert a marker, choose Marker > New and click the trace where you want to insert it.

To create and insert a function...

1. Click the Eqn button, and select a spot on the Display window



2. The Equation editor will appear, make your changes



## Inputs and Outputs

To import or export a design (schematic or layout):

- Choose File > Import (or Export ) from a Schematic or Layout window
- Choose a file type
- Enter a file name

To export ADS Ptolemy designs:

- Choose Tools > Export ADS Ptolemy Design > As WTB Model to RFDE  
OR
- Choose Tools > Export ADS Ptolemy Design > As AMS Model to AMSD-ADE

To import or export data:

- Choose Tools > Data File Tool from a Schematic window  
(for Touchstone, MDIF, CITI, and IC-CAP files)
- Choose Tools > Connection Manager Client from a Schematic window  
(for data from connected instruments)
- Choose Tools > Instrument Server (Windows only)  
(read and write data from various legacy instrument sources in a variety of file formats)

## Formats for Design Exchange

Format	Import	Export
DXF (.dxf)		Layout
EGS Archive Format (_a)	Layout	Layout
EGS Generate Format (_g)	Layout Schematic	Layout
GDSII Stream Format (.gds)	Layout	Layout
Gerber (.gbr)		Layout
Gerber Viewer (.msk, .gbr)		Layout
HPGL/2 (.hpg)	Layout Schematic	Layout
HP IFF (.iff)	Layout Schematic	Layout Schematic
IGES (.igs)	Layout	Layout
Mask File (.msk)	Layout Schematic	Layout
MGC/PCB (.iff)		Layout
Spice (.cir, .cki, .iff, .net)	Schematic	

## Drawing Exchange Format (DXF)

This format was developed by Autodesk for its AutoCAD product to transfer geometric data between systems. Like the mask file format, it provides a simple geometric representation of data. DXF files can be transferred between PC-based or UNIX-based systems.

## Engineering Graphics System (EGS)

This format is a general graphics format used for capturing manually entered designs. EGS has been applied to ICs, Micro-circuits, Hybrids, and PC Board design applications. Using this format, you can easily exchange data with other programs using EGS formats. In addition, EGS facilitates better artwork translation with Advanced Design System.

- The Generate format is a flattened list of EGS primitives specified in the user-defined unit space.
- The Archive Format is a hierarchically organized list of EGS primitives specified in the user-defined unit space. Information such as drawing shapes, layout units, database precision, and grid spacing is included.

### GDSII Stream Format (Calma)

This format is an industry standard for translating final mask data to foundries. Advanced Design System reads GDSII versions 4.0 through 6.0 and writes GDSII version 6.0. Unlike other data formats, GDSII stream format is binary. You cannot easily view or edit a stream format file using a text editor. This format is easily translated between different CAD systems because it represents a highly restrictive data type.

### Gerber

This format refers to various data input formats that Gerber Scientific uses to drive its photoplotters. The Gerber format is used by photoplotters produced by other manufacturers also. The program supports various types of Gerber output via mask files to either the Gerber or DXF translator.

### Gerber Viewer

This format appears as an export file option. It is not a file format, but you can use it to view Gerber or mask files to help verify the correctness of your data if the files meet the following criteria:

- Use either absolute or incremental data coordinates
- Support apertures from D10-D999
- Have data formats from 0.1 to 4.5

### HPGL/2

This format is a subset of the HPGL/2 printer/plotter language. When creating a graph or chart in another tool, you can write the graphics data to an HPGL/2 output file, then import the file into Advanced Design System. In Advanced Design System, the HPGL data is transformed into forms and shapes that can be edited and manipulated like any other drawing. Additional text, annotation, scaling or editing may be added.

### Intermediate File Format (IFF)

This format is an ASCII file with a simple, line-oriented command structure and a fairly rich set of constructs. This format is machine- and application-independent, thus simplifying design data transfer. IFF files are used as the exchange mechanism when transferring designs between Advanced Design System and third-party EDA tools such as Mentor Graphics Design Architect and Cadence Analog Artist.

### Initial Graphics Exchange Specification (IGES)

This format is an approved ANSI standard that is used extensively throughout the computer-aided design and manufacturing world. It can represent both mechanical and electrical design data in two and three dimensions. The IGES standard for the transfer of electrical design data is known as CALS specification. Advanced Design System supports version 4.0 and 5.0 IGES formats. It reads and writes IGES CALS Level 1 (technical illustration) and Level 3 (electrical/electronic applications) files.

### Mask

This format is a simple flat (non-hierarchical) geometric description. The format facilitates the transfer of simple geometric data for final mask processing. Only geometric forms are described in a mask file; simulation data, element parameters, substrate definitions, and hierarchy are not included.

### MGC/PCB

These files are IFF files that are used exclusively for Mentor Graphics design transfers. MGC/PCB files write to a specific location each and every time. When you select this format, the filename and location of the IFF transport is determined automatically.

### Spice

Simulation Program with Integrated Circuit Emphasis (Spice) has become a simulation tool used by engineers throughout the world for simulating circuits of all types. After its development at the University of California Berkeley, Spice has been commercialized and modified by a large number of vendors and also adopted and modified by electronics companies for their own in-house use.

## Formats for Data Transfer

Touchstone (SnP) Format	Description	Usage
SnP	Small signal S, H, Y, Z, or G-parameters. May also include optional noise data (2 port data only). Where n is the number of ports from 1 to 99.	n-Port S-parameter file (SnP) components in the Data Items Library.

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When writing data from a dataset to a file, the variable names are limited to S,H,Y,Z or G, for example, S[1,1], S[1,2], G[1,1], G[1,2]. The variable name is used to determine the type of data.

The first set of data in the dataset that matches the data type (name) will be output. It is not possible to arbitrarily select which data will be output.

CITIfile Format	Description	Usage
CITI	A general data format supported by network analyzers. Capable of storing multiple packages of multi-dimensional data.	S#P #-Port S-parameter file components in the Data Items Library.

There are some specific problems with the current version in writing and/or reading this data format. Refer to the release notes or on the Agilent EEsof support Web site for more information and workarounds.

Agilent IC-CAP Formats	Description	Usage
DUT, MDL, SET	Device under test (DUT), model (MDL), and setup (SET) files from the Agilent IC-CAP software. These files can contain Measured, Simulated, and/or Transformed data.	Once the data is read into a dataset, it can be used with any component (for example, a VtDataset source) that can read data from a dataset.

You can read in IC-CAP data only.

Only simple, scaled expressions with numbers or variables and one operator (either +, -, \<B>, or /) are supported for start, stop, step, and number of points parameters, for example, start= 1 GHZ or stop=icmax/10.

MDIF Formats	Description	Usage
DSCR	Discrete (indexed) tabular and possibly statistical density data.	DAC
GCOMP	Gain compression data	Amplifier and Mixer items in the System - Amps & Mixers library.
GEN_MDIF	Generalized multi-dimensional tables unifying other MDIF formats.	DAC
IMT	Intermodulation product table of mixer intermodulation products between the LO and signal that relates the mixer IM output level to signal input level.	MixerIMT in the System - Amps & Mixers library.
MODEL_MDIF	Nonlinear model parameters	EEFET1, BJTAP, etc.
P2D	Large-signal, power-dependent, 2-port S, H, Y, Z, or G -parameters.	AmplifierP2D item in the System - Amps & Mixers library.
PDF	User defined, piece-wise linear probability density function data.	With expressions in the Statistics tab.

The PDF format is not yet fully supported.

S2D	2-port S, H, Y, Z, or G-parameters with gain compression and optional noise and intermodulation data.	Amplifier S2D, Amplifier, and Mixer items in the System - Amps & Mixers library.
S2PMDIF	Multi-dimensional 2-port, S, Y, Z, H, G signal and optional 2-port noise parameter (Fmin, Gopt, Rn) data.	With S2PMDIF and DAC
SDF	Time-domain voltage data file in HP89440 file format.	TimeFile item in Timed Sources and OutFile item in Sinks library.
SPW	Time-domain voltage data file in Cadence Alta Group SPW format	TimeFile item in Timed Sources and OutFile item in Sinks library.
TIM	Time-domain data	TimeFile item in Timed Sources and OutFile item in Sinks library.

When writing data from a dataset to a file, the variable names are limited to S,H,Y,Z or G, for example, S[1,1], S[1,2], G[1,1], G[1,2]. The variable name is used to determine the type of data.

The first set of data in the dataset that matches the data type (name) will be output. It is not possible to arbitrarily select which data will be will be output.

There are some specific problems with the current version in writing and/or reading this data format. Refer to the release notes or on the Agilent EEsof support Web site for more information and workarounds.

Obsolete Formats: COD, FIR, LAS, SPE, LIST2, and T2D.

## Simulation and Optimization Controllers

### Data Flow Simulation Controller


Use the Data Flow controller to control the flow of mixed numeric and timed signals for all digital signal processing simulations within Advanced Design System. This controller works with the sink components to provide you flexibility to control the duration of the simulation globally or locally.


 DF

```

DF
DF 1
DefaultStart=0.0
DefaultStop=100.0
DefaultTimeUnit=uSec
DefaultSeed=1234567
SchedulerType=ClusterLoop
DeadlockManager=ReportDeadlock
TimeStamp=NoMultiRateDelay
OutVar=""

```

 While you can no longer place multiple controllers on the schematic to simulate the same design with different controller parameters, you can achieve the same functionality by using single-point sweeps on the parameter you are interested in varying.

## DC Simulation Controller

The DC controller provides for both single-point and swept simulations. Swept variables can be related to voltage or current source values, or to other component parameter values. By performing a DC swept bias or a swept variable simulation, you can check the operating point of the circuit against a swept parameter such as temperature or bias supply voltage.



```

DC
DC 1

```

Use the DC controller to:

- Verify the proper DC operating characteristics of the design under test.
- Determine the power consumption of your circuit.
- Verify model parameters by comparing the DC transfer characteristics (I-V curves) of the model with actual measurements.
- Display voltages and currents after a simulation.

A DC simulation is the first analysis for most other analyses. It uses a system of nonlinear ordinary differential equations (ODEs) to solve for an equilibrium point in the linear/nonlinear algebraic equations that describe a circuit once:

- Independent sources are constant valued
- Capacitors and similar items are replaced with open circuits

- Inductors and similar items are replaced with short circuits
- Time-derivatives are constant (zero)

Linear elements are replaced by their conductance at zero frequency

### AC Simulation Controller

A linear AC analysis is a small-signal analysis. For this analysis the DC operating point is found first and then the nonlinear devices are linearized around that operating point. Small-signal AC simulation is also performed before a harmonic-balance (spectral) simulation to generate an initial guess at the final solution.



```
AC
AC1
Start=1.0 GHz
Stop=10.0 GHz
Step=1.0 GHz
```

Use the AC controller to:

- Perform a swept-frequency or swept-variable small-signal linear A simulation.
- Obtain small-signal transfer parameters, such as voltage gain, current gain, transimpedance, transadmittance, and linear noise.

An AC simulation also offers a linear noise simulation option that can include the following noise contributions in its simulation:

- Temperature-dependent thermal noise from lossy passive elements, including those specified by data files.
- Temperature and bias-dependent noise from nonlinear devices.
- Noise from linear active devices specified by two-port data files that include noise parameters.
- Noise from noise source elements.

The noise simulation computes the noise generated by each element, and then determines how that noise affects the noise properties of the network.

### S-Parameter Simulation Controller

The S-Parameter controller is used to define the signal-wave response of an n-port electrical element at a given

frequency. It is a type of small-signal AC simulation that is most commonly used to characterize a passive RF component and establish the small-signal characteristics of a device at a specific bias and temperature.



```
S_Param
SP1
Start=1.0 GHz
Stop=10.0 GHz
Step=1.0 GHz
```

Use the S-Parameter controller to:

- Obtain the scattering parameters (S-parameters) of a component or circuit, and convert the parameters to Y- or Z-parameters.
- Plot, for example, the variations in swept-frequency S-parameters with respect to another changing variable.
- Simulate group delay.
- Simulate linear noise.
- Simulate the effects of frequency conversion on small-signal
- S-parameters in a circuit employing a mixer.

S-parameter simulation normally considers only the source frequency in a noise analysis. Use the Enable AC Frequency Conversion option if you also want to consider the frequency from a mixer's upper or lower sideband.

## Harmonic Balance Simulation Controller

The Harmonic Balance controller is best suited for simulating analog RF and microwave circuits. It is a frequency-domain analysis technique for simulating distortion in nonlinear circuits and systems. Within the context of high-frequency circuit and system simulation, harmonic balance offers the following benefits over conventional time-domain transient analysis:

- It captures the steady-state spectral response directly.
- Many linear models are best represented in the frequency domain at high frequencies.
- The frequency integration required for transient analysis is prohibitive in many practical cases.



```
HarmonicBalance  
HB1  
Freq[1]=1.0 GHz  
Order[1]=3
```

Use the Harmonic Balance controller to:

- Determine the spectral content of voltages or currents.
- Compute quantities such as third-order intercept points, total harmonic distortion, and intermodulation distortion components.
- Perform power amplifier load-pull contour analyses.
- Perform nonlinear noise analysis.

Harmonic Balance enables the multitone simulation of circuits that exhibit intermodulation frequency conversion, including frequency conversion between harmonics. It is an iterative method that assumes that for a given sinusoidal excitation there exists a steady-state solution that can be approximated to a satisfactory accuracy.

## Simulation Overview

Harmonic balance is a frequency-domain analysis technique for simulating distortion in nonlinear circuits and systems. It obtains the frequency-domain voltages and currents to calculate the spectral content of voltages or currents in the circuit. The harmonic balance method is iterative. It is based on the assumption that for a given sinusoidal excitation there exists a steady-state solution that can be approximated to satisfactory accuracy by means of a finite Fourier series.

The Harmonic Balance solution is approximated by truncated Fourier series and this method is inherently incapable of representing transient behavior. The time-derivative can be computed exactly with boundary conditions,  $v(0)=v(t)$ , automatically satisfied for all iterates.

The truncated Fourier approximation + N circuit equations results in a residual function that is minimized. N x M nonlinear algebraic equations are solved for the Fourier coefficients using Newton's method and the inner linear problem is solved by:

- Direct method (Gaussian elimination) for small problems
- Krylov-subspace method (e.g. GMRES) for larger problems

Nonlinear devices (transistors, diodes, etc.) in Harmonic Balance are evaluated (sampled) in the time-domain and converted to frequency-domain via the FFT.

### Advantages

- Harmonic balance captures the steady-state spectral response directly while conventional transient methods need to integrate over many periods of the lowest-frequency sinusoid to reach steady state.
- Harmonic balance is faster at solving typical high-frequency problems that transient analysis can't solve accurately or can only do so at prohibitive costs.
- Harmonic balance is more accurate at solving high frequencies where many linear models are best represented in the frequency domain.

### Convergence

Nonconvergence is a numerical problem encountered by the harmonic balance simulator when it cannot reach a solution, within a given tolerance, after a given number of numerical iterations. There is no one specific solution for solving convergence problems. However, consider the following guidelines:

- Increase the Order (or other harmonic controls); this is the most basic technique for solving convergence problems, if the time penalty for doing so is acceptable.
- Use the Status server window as the main tool in solving convergence problems (set StatusLevel=4). For each Newton iteration the L-1 norm of the residuals throughout the circuit is printed: a "\*" indicates a full Newton step (vs. a Samanskii step).
- Convergence criteria are controlled by Voltage relative tolerance, and Current relative tolerance (in the Options component, under the Convergence tab). In general, convergence speed is improved by increasing these values, but at the expense of accuracy. Similarly, the smaller these values are, the more accurate the results but the slower the convergence.
- Newton convergence issues with Krylov methods (because linear problem solutions can only approximate) can be improved by using better preconditioners.
- Set the Oversample parameter to a value greater than 1.0, such as 2.0 or 4.0. However, remember that although this can often solve convergence problems, it does so at the cost of computer memory and simulation time. For multiple-tone harmonic balance simulations, make sure that the largest signal in the circuit is assigned to Freq[1]. The simulator's FFT algorithm is set up so that aliasing errors are much less likely to affect Freq[1] than any other tone.
- When using a direct linear solver, the blocks of the Harmonic Balance Jacobian inherit the Jacobian matrix ordering from the DC solution process. This matrix ordering can greatly affect the efficiency of the Harmonic Balance Jacobian factorization, and in some circuits show noticeable simulation slowdown. To circumvent this issue, use a DC convergence mode that hasn't changed, e.g. DC\_ConvMode=3.
- For non-convergence due to tight tolerances, monitor the residuals in the Status Server window.
  - Increase I\_AbsTol if the circuit is converging to within a few pA but not quite to  
I\_AbsTol=1pA
  - Increase I\_RelTol if the problem is with nodes associated with large currents
  - Increase I\_AbsTol if the small current nodes are the issue
  - Relax voltage tolerances for failure in the Newton update criterion
- The internal circuit simulator engine in ADS (Gemini) runs from a netlist. ADS writes a netlist file (netlist.log) before invoking Gemini. The order of the components and model definitions in the netlist determine the initial Jacobian matrix ordering. This matrix ordering can affect the efficiency of the Jacobian factorization and cause either a simulation slow down or non-convergence.

- For convergence problems due to errors in the component model equations (incorrect derivatives, etc.) make sure ancient Berkeley MOSFET Level 1, 2, 3 are not the culprit and that the latest model version is used (especially BSIM3 models). Model problems can cause the Newton residual to hit a threshold (greater than the convergence criteria tolerances) and stall the convergence process or even exhibit random jumps (sudden increase in value). Set the device's Xqc parameter to a nonzero value to allow the simulator to use a charge-based model for the gate capacitance. This often enables convergence, but at the cost of extracting an extra SPICE model parameter.

### Sweeps as Convergence Tools

Continuation methods provide a sequence of initial guesses that are sufficiently close to the solution to assure Newton's method convergence in Harmonic Balance. Sweeps can be used to formulate a specialized continuation method geared towards the particular circuit problem.

Sweep a circuit element that, when set to some different value, makes the circuit more linear. For instance, in an amplifier circuit there may be a resistor that can be used to lower the amplifier's gain. The simulator may be able to find a solution to the circuit under a low-gain condition. Then, if the component's value is swept toward the desired value, the simulator may be able to find a final solution. Start with a value that works, and stop with the desired value. Also, select Restart, under the Params tab. Usually, a better initial guess at each step helps the simulator to converge.

The two main ways to perform sweeps are:

- HB sweep within the HB controller. This is preferred for most sweeps, except frequency.
- Parameter sweep using a separate sweep controller.

### Convergence and Samanskii Steps

The Samanskii steps can significantly speed up the solution process. However, using an approximate Jacobian, particularly for a larger number of iterations, may result in poor or even no convergence. The constant is used in two ways. First, it becomes a more absolute measure when it is smaller. It then approaches the requirement that each iteration reduces the relevant norm by one-third.

Decreasing the Samanskii constant beyond a certain point (which in turn depends on the quality of the most recent Newton step) will make no difference. However, setting the Samanskii constant to zero will effectively disable any Samanskii steps altogether.

Increasing the Samanskii constant relaxes this requirements in general, but the condition becomes more dependent on the quality of the standard most recent Newton iteration. In other words, a more rapid convergence of the Newton step would also require better convergence of the Samanskii steps.

### Convergence and Arc-Length Continuation

Arc-length continuation is an extremely robust algorithm. If it fails, try all other convergence remedies first before adjusting arc-length parameters

- MaxStepRatio controls the maximum number of continuation steps (default 100)
- MaxShrinkage controls the minimum size of the arc-length step (default 1e-5)
- ArcMaxStep limits the maximum size of the arc-length step (default is 0, i.e. no limiting)
- ArcMinValue & ArcMaxValue define the allowed range for the variation of the continuation parameter

### Circuit Envelope Simulation Controller

The Circuit Envelope controller is best suited for a fast and complete analysis of complex signals such as digitally modulated RF signals. It combines features of time and frequency-domain representation by permitting input waveforms to be represented in the frequency domain as RF carriers, with modulation "envelopes" that are represented in the time domain.



```
Envelope  
Env1  
Freq[1]=1.0 GHz  
Order[1]=3  
Stop=100 nsec  
Step=1 nsec
```

Circuit Envelope is highly efficient in analyzing circuits with digitally modulated signals, because the transient simulation takes place only around the carrier and its harmonics. In addition, its calculations are not made where the spectrum is empty.

- It is faster than Harmonic Balance, for a given complex signal Spice, assuming most of the frequency spectrum is empty
- It does not compromise in Signal complexity, unlike time-varying HB or Shooting Method Component accuracy, unlike Spice, Shooting Method, or DSP
- It adds physical analog/RF performance to DSP/system simulation with real-time co-simulation with ADS Ptolemy
- It is integrated in same design environment as RF, Spice, DSP, electromagnetic, instrument links, and physical design tools

### Advantages over Harmonic Balance

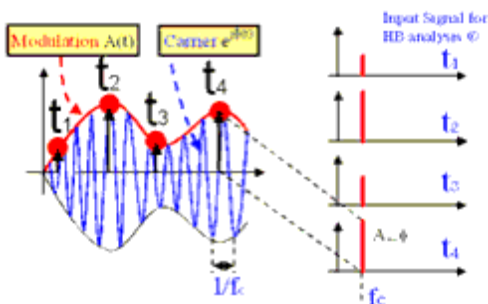
- In Harmonic Balance, if you add nodes or more spectral frequencies, the RAM and CPU requirements increase geometrically. Krylov improved this, but it's still a limitation of Harmonic Balance because the signals are inherently periodic.
- Conversely the penalty for more spectral density in Circuit Envelope is linear: just add more time points by increasing TSTOP. The longer you simulate, the finer your resolution bandwidth.
- Doing a large number of simple 1-tone HB simulations is effectively faster and less RAM intensive than one huge HB simulation.
- With a circuit envelope simulation the amplitude and phase at each spectral frequency can vary with time, so the signal representing the harmonic is no longer limited to a constant, as it is with harmonic balance.

### Limitations

1. More occupied spectrum than unoccupied spectrum.  
You're carrying more overhead with frequency-domain assumptions and harmonics than necessary. Use SPICE.
2. Everything baseband. Depends.
  - If everything linear, use AC/S-parameter (for noise or budget)
  - If everything nonlinear or digital, use SPICE.
  - If everything logic/behavioral, use PTOLEMY.
3. Occupied spectrum is relatively sparse.  
If you can do what you want using Harmonic Balance, you should. Post-processing, optimization, and yield are simpler and faster.

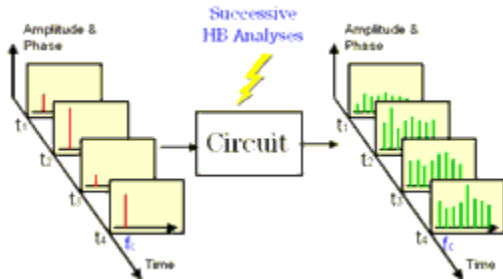
### Simulation Process

1. Transform input signal



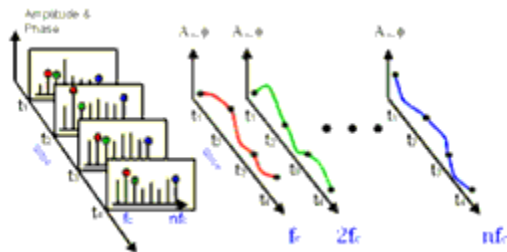
Each modulated signal can be represented as a carrier modulated by an envelope -  $A(t) \cdot e^{j\omega_c t}$ . The values of amplitude and phase of the sampled envelope are used as input signals for Harmonic Balance analyses.

2. Frequency Domain Analysis



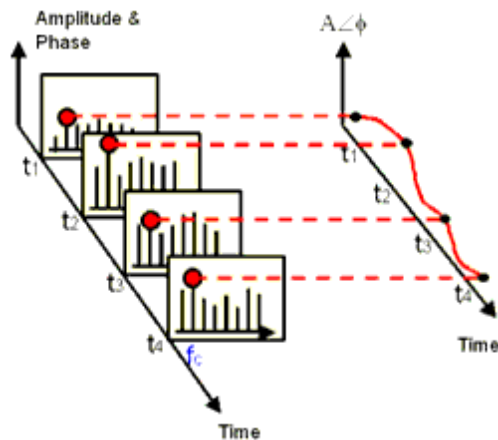
Harmonic Balance analysis is performed at each time step. This process creates a succession of spectra that characterize the response of the circuit at the different time steps.

### 3. Time Domain Analysis



Circuit Envelope provides a complete non steady-state solution of the circuit through a Fourier series with time-varying coefficients.

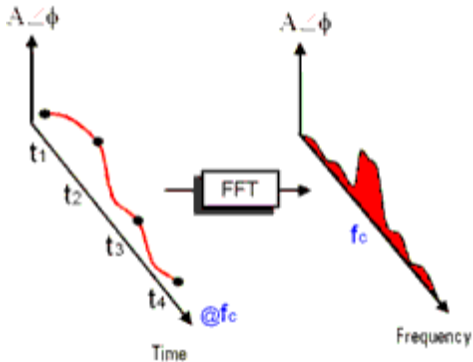
### 4. Extract Data from Time Domain



Selecting the desired harmonic spectral line ( $f_c$  in this case), it is possible to analyze:

- Amplitude vs. Time (Oscillator start up, Pulsed RF response, AGC transients)
- Phase ( $f$ ) vs. Time ( $t$ ) (VCO instantaneous frequency ( $df/dt$ ), PLL lock time)
- Amplitude & Phase vs. Time (Constellation plots, EVM, BER)

### 5. Extract Data from Frequency Domain



By applying FFT to the selected time-varying spectral line it is possible to analyze:

- Adjacent Channel Power Ratio (ACPR)
- Noise Power Ratio (NPR)
- Power Added Efficiency
- Reference frequency feedthrough in PLL
- Higher order intermods (3rd, 5th, 7th, 9th)

### Simulation Steps

<ol style="list-style-type: none"> <li>1. Define baseband signal modulation             <ul style="list-style-type: none"> <li>• Predefined sources</li> <li>• Equations</li> <li>• I &amp; Q data vs. time data from DSP simulation</li> </ul> </li> <li>2. Define RF carrier frequencies, time step and duration of the simulation</li> <li>3. Compute time-varying Fourier coefficients</li> <li>4. Post-process and display results</li> </ol>	OR	<ol style="list-style-type: none"> <li>1. Define input signal(s) with modulation - amplitude, phase, frequency, I/Q, etc.</li> <li>2. Define the time step</li> <li>3. Simulator computes Fourier coefficients versus time:</li> <li>4. Fourier transforms are computed to display frequency spectrum around any tone (if necessary)</li> </ol>
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### Typical Analyses

- Intermodulation distortion.
- Amplifier spectral regrowth and adjacent channel power leakage.
- Oscillator turn-on transients and frequency output versus time in response to a transient control voltage.
- PLL transient responses.
- AGC and ALC transient responses.
- Circuit effects on signals having transient amplitude, phase, or frequency modulation.
- Amplifier harmonics in the time domain.
- Subsystems using modulation signals such as multilevel FSK, CDMA, or TDMA.

- Third-order-intercept and higher-order intercept analyses of amplifiers and mixers.
- Time-domain optimization of transient responses.

### Typical Applications

#### Time Domain Data Extraction

Selecting the desired harmonic spectral line it is possible to analyze:

- Amplitude vs. Time
  - Oscillator start up
  - Pulsed RF response
  - AGC transients
- Phase vs. Time
  - VCO instantaneous frequency, PLL lock time
- Amplitude & phase vs. time
  - Constellation plots
  - EVM, BER

#### Frequency Domain Data Extraction

By applying FFT to the selected time-varying spectral line it is possible to analyze:

- Adjacent Channel Power Ratio (ACPR)
- Noise Power Ratio (NPR)
- Power added efficiency
- Reference frequency feedthrough in PLL
- Higher order intermods (3rd, 5th, 7th, 9th)

### LSSP Simulation Controller

The large-signal S-parameter simulation controller facilitates the computation of large-signal S-parameters in nonlinear circuits.



```
LSSP
HB1
Freq[1]=1.0 GHz
Order[1]=3
LSSP_FreqAtPort[1]=
```

Large-signal S-parameters are based on a harmonic balance simulation of the full nonlinear circuit. Unlike S-parameters, large signal S-parameters can change as power levels are varied because the harmonic balance simulation includes nonlinear effects such as compression.

## XDB Simulation Controller

The XDB simulation controller computes the gain compression point of an amplifier or mixer. It sweeps the input power upward from a small value, stopping when the required amount of gain compression is seen at the output.



```
XDB
HB1
Freq[1]=1.0 GHz
Order[1]=3
GC_XdB=1
GC_InputPort=1
GC_OutputPort=2
GC_InputFreq=1.0 GHz
GC_OutputFreq=1.0 GHz
GC_InputPowerTol=1e-3
GC_OutputPowerTol=1e-3
GC_MaxInputPower=100
```

## Transient/Conv. Simulation Controller

The transient and convolution simulation controllers solve a set of integro-differential equations that express the time dependence of the currents and voltages of the circuit. The result of such an analysis is nonlinear with respect to time and, possibly, a swept variable.



```
Tran  
Tran1  
StopTime=100.0 nsec  
MaxTimeStep=1.0 nsec
```

Use the Transient/Convolution controller to perform:

- SPICE-type transient time-domain analysis.
- Nonlinear transient analysis on circuits that include the frequency-dependent loss and dispersion effects of linear models, or Convolution analysis.

A transient analysis is performed entirely in the time-domain. It does not account for the frequency-dependent behavior of distributed elements.

A convolution analysis represents distributed elements in the frequency domain to account for their frequency-dependent behavior.

## Transient Simulation and Convergence

In Transient analysis a numerical integration algorithm is employed at each time point to approximate the differential equations into algebraic equations. Integration methods are used to replace the time derivative with a discrete-time approximation

## Time Step Control Characteristics

### Local Truncation Error

- Estimates the LTE made on every capacitor and inductor
- Determines the time step size to ensure the largest LTE remains within the accepted tolerance
- The estimated LTE is inversely proportional to TruncTol
- The accepted tolerance depends upon the relative and truncation tolerances set for the current and voltage. It is proportional to  $I\_RelTol \times TruncTol$  and  $V\_RelTol \times TruncTol$

### Iteration-Count

- Determines the time step size based on the number of Newton iterations required for previous time point
- No direct relationship between iterations and LTE

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- Effectively controlled by Max time step (for linear circuits)

### Fixed

- The time step is fixed and equal to Max time step

### Break Points

- Generated by built-in independent sources whenever an abrupt change in slope occurs
- Ensure that corners in waveforms are not missed
- ADS always places time points on a break point (except fixed time step)
- Backward Euler is used on time points that are the first time step after break points
- The step size is reduced when time point is close to a break point

## Transient Convergence Tips

1. For initial Transient analysis, try to use  $I\_RelTol = V\_RelTol = 1e-3$ , and tighten these values only when higher accuracy is needed. Simulation will run much faster with these settings compared to  $1e-6$ .
2. Transient analysis convergence problems are often caused by jumps in the solution. This most often occurs in circuits with overly simplified models that exhibit positive feedback, or when the circuit contains nodes that do not have a capacitive path to ground. Add a small capacitor from the troublesome node to ground and give a complete capacitance model when specifying the nonlinear device model parameters.
3. Generally analog circuits are sensitive to truncation error due to their relative long time constants. Use LTE time step control to ensure the accuracy of the results.
4. Backward Euler (Gear1 or  $Mu=0$  in Trapezoidal) and Gear2 are stable for all stable and some unstable differential equations. However, trapezoidal rule are stable only on stable differential equations. Switch to Gear1 or Gear2 when trapezoidal rule fails on unstable differential equations.

## Typical Convergence Problems

### Capacitor model problems

- Use simplified device models that do not include capacitance model or incomplete capacitance model give a complete capacitance model when specifying nonlinear device model parameters, in junction capacitance, include both depletion (at least) and diffusion capacitances
- Discontinuous jumps in waveforms when circuit contains nodes have no capacitive path to ground add small capacitor to ground or specify  $C_{min}$
- Capacitance model does not conserve charge GaAsFET Statz's, MOSFET Meyer's capacitance models switch to charge based model
- Large floating capacitors that are similar to the small-floating resistor problem in DC (finite precision problem)

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check capacitance unit, use smaller capacitance

- Discontinuous capacitance models in user defined model, SDD device fix the model

### Slow Transient analysis

- Make sure I\_RelTol and V\_RelTol are set to 1e-3 or not set at all
- Decrease these values when higher accuracy is needed

### Oscillator circuit does not oscillate

- Apply a short pulse at the beginning of the simulation
- Avoid using Gear2 or backward Euler

### Circuit exhibits ringing or divergence

- Reduce Mu value from 0.5 toward 0 if trapezoidal rule is used
- Use Gear1 or Gear2

### Circuit does not converge at first time point

- Reduce Min time step

### Convergence Hints

#### Add break points

Use piecewise linear source to add break points to the region where the waveform changes abruptly

#### Reduce max time step

Ensure enough time points for sharp edges

Increase Max iterations per time step

Increase to 50 or more to increase the possible number of Newton iterations on each time step

Increase I\_AbsTol

Try 1e-10 instead of the default 1e-12

Relax TruncTol

Increase this value 10 times or more to relax LTE tolerance

Relax I\_Reltol and V\_Reltol

Increase to 1e-3 to relax Newton convergence tolerance as well as LTE tolerance

Try different integration methods

Switch from trapezoidal to Gear's method

Using Convolution

- Don't set any convolution parameters (let the adaptive algorithm figure it out)
- Set ImpMaxFreq first (larger than signal bandwidth)
- Set convolution parameters on component, not controller, when possible
- Don't allowed measured data to be extrapolated (either set ImpMaxFreq or provide more data)

Convolution Modeling for Time-Domain Simulation

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- In time-domain simulation, simulate devices that can only be defined in the frequency domain
  - Transmission lines with dispersion
  - Devices with frequency-dependent loss
  - Measured frequency-domain data
- Convolution is the key
  - Inverse Fourier transform of frequency-domain data produces the impulse response  $h(t)$
  - The impulse response is convolved with time-domain signal

### Time and Frequency Range

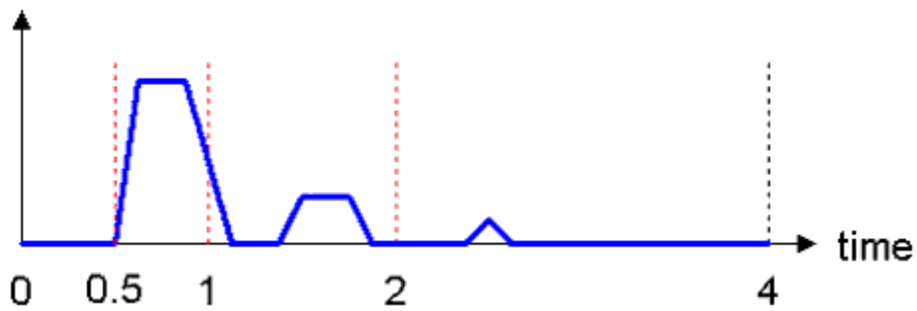
- Impulse response is computed from the inverse Fourier transform of frequency-domain response frequency is uniformly sampled from 0 to some upper value
- Upper frequency sets the time-domain spacing of the impulse response
- Frequency spacing sets the length of the impulse response

### Adaptive Impulse Response Calculation

- Estimate of system bandwidth is made from source frequencies and rise times - initial guess at  $f_{max}$
- Build a trial impulse response with 32 timepoints  
very coarse frequency spacing
- Build a second impulse response with 64 timepoints  
less coarse frequency spacing
- Keep doubling the number of timepoints until a good impulse response is obtained  
increase  $f_{max}$ , decrease  $Df$
- $y_{11}$  and  $y_{12}$  may be sampled with different  $f_{max}$  and  $Df$
- Adaptive calculation is only done if `ImpDeltaFreq` is not specified  
don't set `ImpDeltaFreq` if you don't have to

### Good Impulse Responses

- Compare impulse responses with  $N$  and  $2N$  points. The second impulse response is twice as long in time domain and has half the frequency spacing.
- An impulse is considered "good" when no appreciable energy is present in the second half of the impulse response if energy is present in the second half, implies either that the impulse is not long enough or it is noncausal
- If not good, Controller keeps doubling the length
- Controller also tries doubling the maximum frequency, giving smaller impulse timesteps

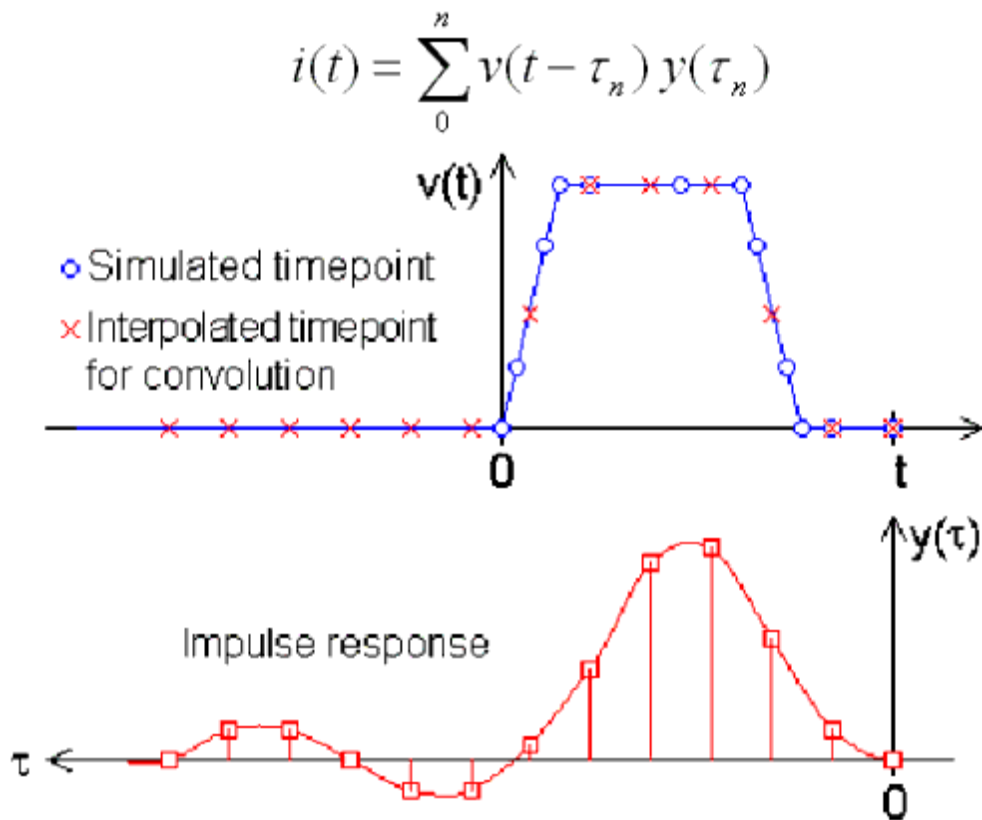


### Interpolation

- The impulse response is sampled with a uniform timestep, but is not guaranteed to match the simulation timestep. The simulation may even be using a variable timestep.
- Interpolate the signal  $v(t)$  to match the timepoints in the impulse response
- Don't interpolate the impulse response because the Fourier transform of the interpolated impulse response would no longer match the original frequency response

### Impulse Evaluation

- Signal response at time zero extends back to minus infinity
- Evaluate the integral as a sum



### Solving an Invalid Impulse Response

This is the most commonly encountered problem during convolution. It does not necessarily imply noncausality but means that significant energy is present in the second half of the impulse response. In addition, simulation results may or may not be valid.

- Set ImpMaxFreq or ImpDeltaFreq. Set ImpMaxFreq first, typically only for measured data.
- For every component that generates this message, fix each component one at a time to simplify the design.

### Viewing an Impulse Response

- In an S-parameter simulation, analyze over the given frequency spacing and maximum frequency inverse Fourier transform the response by plotting  $ts(x)$
- In the time domain, apply an impulse and simulate plot the transient result  
the pulse risetime is used to set fmax and thus can influence the impulse response

### Setting ImpMaxFreq and ImpDeltaFreq

Generally a good impulse response can be found without manually setting ImpMaxFreq and ImpDeltaFreq

- If ImpMaxFreq is set, the adaptive algorithm tries different lengths but doesn't modify fmax
- If ImpDeltaFreq is set, the adaptive algorithm is disabled and the impulse is computed from ImpDeltaFreq and ImpMaxFreq
- Set ImpMaxFreq on the component, then set ImpDeltaFreq on component if necessary, and finally, set ImpMaxFreq on the transient controller if necessary
- For transmission lines, set ImpMaxFreq to at least  $n/td$ , where  $td$  is the delay time and  $n$  is a small integer (2-3)
- For lowpass and bandpass filters, set ImpMaxFreq to at least twice the upper passband edge

### Measured Data with S2P Component

- The algorithm that computes the impulse response has no special knowledge of the component it's working on and assumes data is available at any desired frequency. It has no knowledge of flow and fhigh or frequency spacing of measured data
- S2P interpolates and extrapolates data as needed
- Be sure to supply good data to prevent dangerous extrapolation extends down to DC and up to fmax
- Set ImpMaxFreq on S2P component to match frequency limits in datafile (avoid extrapolation)
- Typically there is not enough frequency-domain data in the S2P file for use in the simulation

Given a pulse with a risetime of  $tr$ , the equivalent bandwidth is  $2.2/tr$  (0.1 ns risetime represents a 22 GHz bandwidth)

Package models typically must be measured up to 10x higher than the signal frequency to represent transmission line effects well

### Solving a Noncausal Impulse Response

This is the second most commonly encountered problem during convolution. The Time-domain simulation starts at time zero and moves forward in time, computing the value of next timepoint from all previous timepoints. And the Controller deals with this by introducing a delay to force causality.

Length of delay set to ImpNoncausalLength (default=32) with timestep set by default ImpMaxFreq  
Simulation results will not be accurate because of the added delay, especially if the delay is added in a critical timing or phase path.

All physically realizable devices are causal (the output is dependent only on past states and not any future states) while noncausal devices are nonphysical. Some ADS components, user-defined data or equations may be noncausal.

- Frequency-dependent real part with constant imaginary part, for example resistance as a function of frequency without any reactance
- Constant real and constant non-zero imaginary part
- Negative time delays
- INDQ, CAPQ, PLCQ, SLCQ have problems in some modes

### RF Budget Controller

Use the Budget controller for budget analysis of an RF system. This RF system budget analysis enables you to determine the linear and nonlinear characteristics of an RF system comprising a cascade of two-port, two-pin linear or nonlinear components.

The Budget controller includes a large number of built-in budget measurements and improved budget noise measurements.



```
Budget
Budget
NonlinearAnalysis=yes
NonlinearHarmonicOrder=3
CmpMaxPin=40_dBm
NoiseFreqSpan=1 Hz
NoiseFreqStep=0 Hz
NoiseResolutionBW=1 Hz
TableComponentFormat=Columns
MeasurementFrequencyUnit=Hz
MeasurementAngleUnit=degrees
AutoFormatDisplay=no
OutputCSVFile=no
RunCommand=no
SystemCommand=""
Measurement[1]=
```

Use the RF Budget Controller to

- Modify simulations using tuning, parameter sweeps, optimization, yield analysis, etc.
- Include AGC loops to control gain and set power levels at specific points in the RF system.
- Select alternate budget paths.

### Nominal Optimization Controller

Use the Nominal Optimization controller in combination with Goal components to satisfy predetermined performance goals. Optimizers that compare computed and desired responses and modify design parameter nominal values to bring the computed response closer to that desired can be selected from within the Nominal Optimization controller setup.



Optim  
 Optim1  
 OptimType=Random    UseAllGoals=yes  
 MaxIters=25            SaveCurrentEF=no  
 DesiredError=0.0  
 StatusLevel=4  
 FinalAnalysis="None"  
 NormalizeGoals=no  
 SetBestValues=yes  
 Seed=  
 SaveSols=yes  
 SaveGoals=yes  
 SaveOptimVars=no  
 UpdateDataset=yes  
 SaveNominal=no  
 SaveAllIterations=no  
 UseAllOptVars=yes



Goal  
 OptimGoal1  
 Expr=  
 SimInstanceName=  
 Min=  
 Max=  
 Weight=  
 RangeVar[1]=  
 RangeMin[1]=  
 RangeMax[1]=

## Monte Carlo Controller

Use the Monte Carlo analysis controller to randomly vary network statistical parameter values according to statistical distributions to get the overall performance variation. This process involves simulating the design over a given number of trials in which the statistical variables have values that vary randomly about their nominal values with specified probability distribution functions.



MonteCarlo  
 MonteCarlo1  
 SimInstanceName[1]=  
 NumIters=250  
 Seed=  
 SaveSols=yes  
 SaveSpecs=yes  
 SaveRandVars=yes  
 UpdateDataset=no  
 SaveAllIterations=yes  
 UseAllSpecs=yes  
 StatusLevel=2

## Yield Analysis Controller

Use the Yield Analysis controller in combination with a Yield Specification component to vary a set of statistical parameter values, using specified probability distributions, to determine how many possible combinations result in satisfying predetermined performance requirements. This process involves simulating the design over a given number of trials in which the statistical variables have values that vary randomly about their nominal values with specified probability distribution functions. The numbers of passing and failing trials are recorded and these numbers are used to compute an estimate of the yield.



Yield

Yield1

NumIters=250

PPT\_Mode=none

ShadowModelType=none

Seed=

SaveSolns=yes

SaveSpecs=no

SaveRandVars=no

UpdateDataset=no

SaveAllIterations=no

UseAllSpecs=yes

StatusLevel=2

 A blue-bordered icon for the Yield Specification component, containing the text "YIELD SPEC".
 

YIELD SPEC

YieldSpec

Spec1

Expr=

SimInstanceName=

Min=

Max=

Weight=

RangeVar[1]=

RangeMin[1]=

RangeMax[1]=

## Yield Optimization Controller

Use the Yield Optimization controller in combination with a Yield Specification component to perform multiple yield analyses with the goal of adjusting the nominal values of the statistical variables to maximize the yield estimate.

During yield optimization, each yield improvement is referred to as a design iteration.

 YIELD OPTIMIZATION

YieldOptim  
 YieldOpt1  
 NumIters=5  
 PPT\_Mode=none  
 ShadowModelType=none  
 Seed=  
 SaveSolns=no  
 SaveSpecs=yes  
 SaveRandVars=no  
 UpdateDataset=yes  
 SaveAllIterations=no  
 UseAllSpecs=yes  
 StatusLevel=4  
 RestoreNomValues=

YIELD SPEC

YieldSpec  
 Spec1  
 Expr=  
 SimInstanceName=  
 Min=  
 Max=  
 Weight=  
 RangeVar[1]=  
 RangeMin[1]=  
 RangeMax[1]=

Design of Experiments Controller

Use the Design of Experiments (DOE) controller in combination with DOE Goal components to perform an experiment and collect response data. You can then analyze the data using statistical methods. Sequential application of this methodology can be used to improve the statistical performance of a given circuit or system. Because of an inherent compromise between statistical performance prediction accuracy and the number of input variables, a screening experiment is used to identify variables that contribute significantly to performance variation. Next a refining experiment can be used to hone in on the target statistical response.

 DOE

DOE  
 DOE1  
 ExperimentType=2kmp  
 FracElem=0  
 SaveSolns=no  
 SaveDoeGoals=no  
 SaveDoeVars=no  
 UpdateDataset=no  
 SaveAllIterations=no  
 UseAllDoeGoals=yes  
 StatusLevel=2

DOE GOAL

DoeGoal  
 DoeGoal1  
 Expr=  
 SimInstanceName=  
 Min=  
 Max=  
 Weight=  
 RangeVar[1]=  
 RangeMin[1]=  
 RangeMax[1]=

## Additional Resources

Use the following ADS resources to optimize your design tasks.

### Documentation

The Agilent EEsof Product Documentation home page on the Web includes information and links to complete documentation for all EEsof product. For ADS it currently provides documentation for ADS 1.5 onward. The documentation provided on the website includes the following.

- Release Notes list of known problems.
- New highlights of what is new in the current release.
- Manuals descriptions and links to the complete documentation set.
- Examples descriptions of examples used to solve real-life design tasks.
- DesignGuides descriptions and links to application-focussed DesignGuide documentation.
- Quick Start web-based version of the Quick Start manual.
- Search global search of ADS documentation.
- PDF Files printable files for all ADS documentation.

The Agilent EEsof Product Documentation Web site is at <http://www.agilent.com/find/eesof-docs>

### Website

The Agilent EEsof EDA home page on the Web includes information and links to the following resources.

- EDA library articles, papers, application notes, and other publications.
- Foundry Partners links to leading IC manufacturers who provide design libraries for ADS.
- Success Stories what real users, large and small, have to say about their successes with ADS.
- Training Classes current list of training courses being offered worldwide.
- Applications applications information including downloadable example files and publications.
- Agilent EEsof Knowledge Center database of information, discussions, and downloads.

The Agilent EEsof EDA Web site is at <http://www.agilent.com/find/eesof>

### Support Contacts

Agilent EEsof worldwide technical support is available Monday through Friday. The toll-free North America hotline is

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open 6:00 am to 5:00 pm PT. Throughout Europe, the localized Online Technical Support Centers are open 8:30 am to 5:30 pm, local time; throughout Asia, the localized Customer Response Centers are open 9:00 am to 6:00 pm, local time.

The e-mail addresses for the various regions are listed below. However, for both the regional e-mail addresses and local telephone numbers for more than 25 countries, please refer to the Agilent EEsof Support Web site at <http://www.agilent.com/find/eesof-supportcontact>

### North America

Phone: 1 800 47 EEsof (473-3763) □ Fax: 707-577-3511

e-mail: [eesof\\_support@agilent.com](mailto:eesof_support@agilent.com)

Europe: e-mail: [eesof-europe\\_support@agilent.com](mailto:eesof-europe_support@agilent.com)

Japan: e-mail: [eesof-japan\\_support@agilent.com](mailto:eesof-japan_support@agilent.com)

Korea: e-mail: [eesof\\_korea@agilent.com](mailto:eesof_korea@agilent.com)

Asia: e-mail: [eesof-asia\\_support@agilent.com](mailto:eesof-asia_support@agilent.com)